



ATBTLC1000XR/ZR

Ultra-Low Power BLE ATBTLC1000-XR1100A SiP/ ATBTLC1000-ZR110CA Module Datasheet

Introduction

The Microchip ATBTLC1000-XR1100A is an ultra-low power Bluetooth® low energy System in a Package (SiP) with Integrated MCU, Transceiver, Modem, MAC, PA, Transmit/Receive (T/R) Switch, and Power Management Unit (PMU). It can be used as a Bluetooth Low Energy link controller or data pump with external host MCU. The host interface between MCU and ATBTLC1000-XR1100A is a UART with hardware flow control.

The Bluetooth® SIG qualified protocol stack is stored in a dedicated ROM. The firmware includes L2CAP service layer protocols, Security Manager, Attribute protocol (ATT), Generic Attribute Profile (GATT), and the Generic Access Profile (GAP). Additionally, example applications are available for application profiles such as proximity, thermometer, heart rate, blood pressure and many other SIG-defined profiles.

The ATBTLC1000-XR1100A provides a compact footprint and various embedded features such as a 26 MHz crystal oscillator. It provides the right solution for the customer, whose BLE design requires full features, using low power consumption and minimal PCB space.

The ATBTLC1000-ZR110CA is a fully certified module that contains the ATBTLC1000-XR1100A and all external circuitry required including a ceramic high-gain antenna. The user needs to place the module into their PCB design, provide power, a 32.768 kHz Real Time Clock or crystal, and an I/O path for interfacing with the host MCU.

Microchip BluSDK offers a comprehensive set of tools including reference applications for several Bluetooth SIG-defined profiles and a custom profile. The BluSDK will help the user to quickly evaluate, design and develop BLE products with the ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA.

The ATBTLC1000-XR1100A and associated ATBTLC1000-ZR110CA module have passed the Bluetooth SIG certification for interoperability with the Bluetooth Low Energy 5.0 specification, QDID: [117593](#).

Features

- 2.4 GHz Transceiver and Modem:
 - -91.5 dBm receiver sensitivity
 - -55 dBm to +3.5 dBm programmable TX output power
 - Integrated T/R switch
 - Single wire antenna connection (ATBTLC1000-XR1100A)
 - Incorporated chip antenna (ATBTLC1000-ZR110CA)
- Processor Features:
 - ARM® Cortex® M0 32-bit processor
 - Serial Wire Debug (SWD) interface

- Four-channel Direct Memory Access (DMA) controller
- Brown-out Detector and Power-on Reset (POR)
- Watchdog timer
- Memory:
 - 128 KB embedded Random Access Memory (RAM)
 - 128 KB embedded ROM
- Hardware Security Accelerators:
 - Advanced Encryption Standard (AES)-128
 - Secure Hash Algorithm (SHA)-256
- Peripherals:
 - 22 digital and 4 mixed-signal General Purpose Input Outputs (GPIOs) with 96 kOhm internal programmable pull up or down resistors and retention capability, and one wake-up GPIO with 96 kOhm internal pull up resistor⁽¹⁾
 - Two Serial Peripheral Interface (SPI) Master/Slave⁽¹⁾
 - Two Inter-Integrated Circuit (I²C) Master/Slave
 - Two UART⁽¹⁾
 - Three-axis quadrature decoder⁽¹⁾
 - Four Pulse Width Modulation (PWM) channels⁽¹⁾
 - Three General Purpose Timers and one Wake-up Timer⁽¹⁾
 - 2-channel 11-bit Analog-to-Digital Converter (ADC)⁽¹⁾
- Host Interface:
 - Host MCU can control through UART with hardware flow control
 - Only two microcontroller GPIO lines necessary
 - One interrupt pin from ATBTLC1000, which can be used for host wake-up
- Clock:
 - Integrated 26 MHz RC oscillator
 - Integrated 2 MHz RC oscillator
 - 26 MHz crystal oscillator (XO)
 - 32.768 kHz Real Time Clock crystal oscillator (RTC XO)
- Ultra-Low Power:
 - 1.88 μ A sleep current
 - 4.78 mA peak TX current ⁽²⁾
 - 5.66 mA peak RX current
 - 15.8 μ A average advertisement current⁽³⁾
- Integrated Power Management:
 - 1.8V to 4.3V battery voltage range
 - Fully integrated Buck DC/DC converter
- Temperature Range:
 - -40°C to 85°C
- Package:
 - 49-pin FLGA SiP package 5.50 mm x4.50 mm
 - 35-pin module package 10.541 mm x7.503 mm

- BT SIG QDID: [117593](#)

Note:

1. Usage of this feature is not supported by the BluSDK. The datasheet will be updated once the support for this feature is added in BluSDK.
2. TX output power - 0 dBm
3. Advertisement channels - 3 ; Advertising interval - 1 second ; Advertising event type - Connectable undirected; Advertisement data payload size - 31 octets

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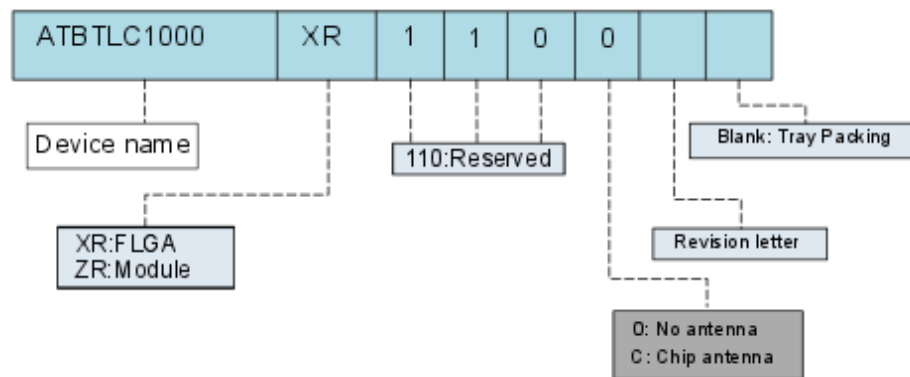
1. Ordering Information

Table 1-1. Ordering Details

Model Number	Ordering Code	Package	Description	Regulatory Information
ATBTLC1000-XR1100A	ATBTLC1000-XR1100A	5.5 mm x 4.5 mm	ATBTLC1000 SiP tray	NA
ATBTLC1000-ZR110CA	ATBTLC1000-ZR110CA	7.5 mm X 10.5 mm	ATBTLC1000 chip antenna module	FCC, ISED, CE, MIC, KCC, NCC

The following figure illustrates the ATBTLC1000-XR1100A module marking information.

Figure 1-1. Marking Information



2. Package Information

Table 2-1. ATBTLC1000-XR1100A SiP 49 Package Information

Parameter	Value	Units	Tolerance
Package size	5.50 x 4.50	mm	±0.05 mm
Pad count	49		
Total thickness	1.40	mm	max
Tolerance (maximum pad pitch)	0.40	mm	±0.05 mm
Pad width	0.21		
Exposed pad size	0.50 x 0.50		

Note: For drawing details, see [12.1 ATBTLC1000-XR1100A Package Outline Drawing](#).

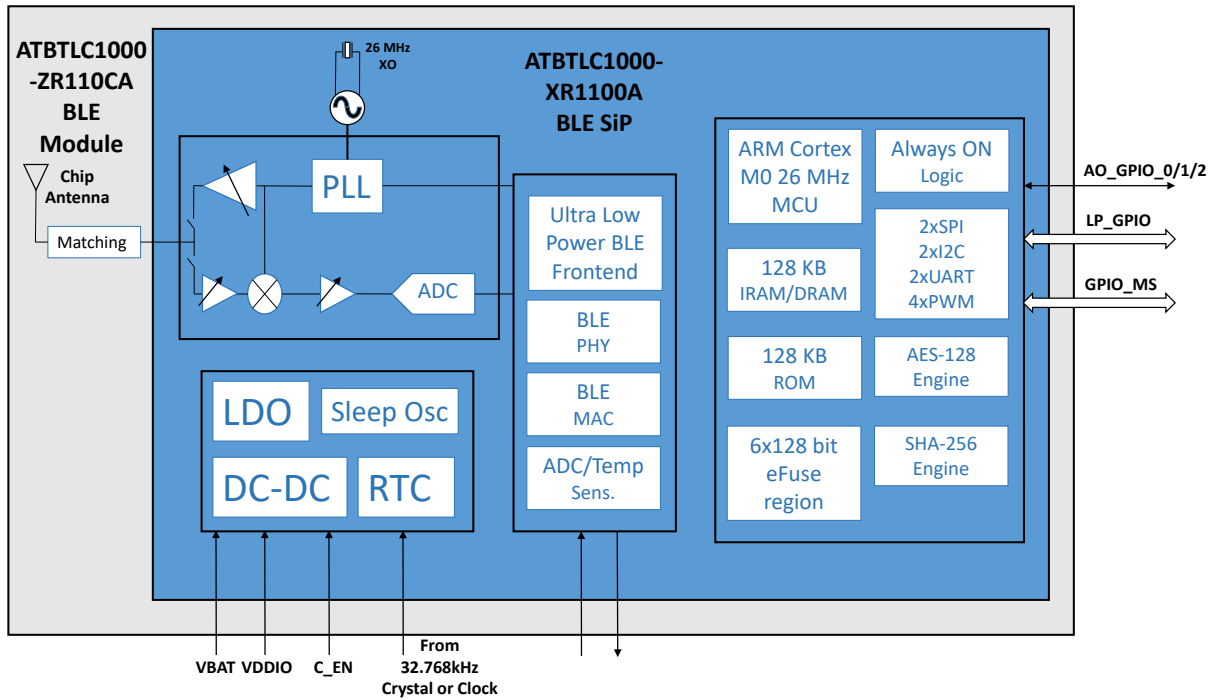
Table 2-2. ATBTLC1000-ZR110CA Module Information

Parameter	Value	Units	Tolerance
Package size	7.503 x 10.541	mm	Untoleranced dimension
Pad count	34		
Total thickness	1.868	mm	Untoleranced dimensions
Pad pitch	0.61		
Pad width	0.406		
Exposed pad size	2.705 x 2.705		

Note: For drawing details, see [Module PCB Package Outline Drawing](#).

3. Block Diagram

Figure 3-1. Block Diagram



4. Pinout Information

The ATBTLC1000-XR1100A is offered in an exposed pad 49-pin SiP package. This package has an exposed paddle that must be connected to the system board ground. The SiP package pin assignment is shown in the figure below. The color shading is used to indicate the pin type as follows:

- Red – analog
- Green – digital I/O (switchable power domain)
- Blue – digital I/O (always-on power domain)
- Yellow – power
- Purple – PMU
- Shaded green/red – configurable mixed-signal GPIO (digital/analog)

The ATBTLC1000-ZR110CA module is a castellated PCB with the ATBTLC1000-XR1100A integrated with a matched chip antenna. The pins are identified in the pin description table. The ATBTLC1000-ZR110CA also contains a paddle pad on the bottom of the PCB that must be soldered to the system ground.

Figure 4-1. ATBTLC1000-XR1100A Pin Assignment

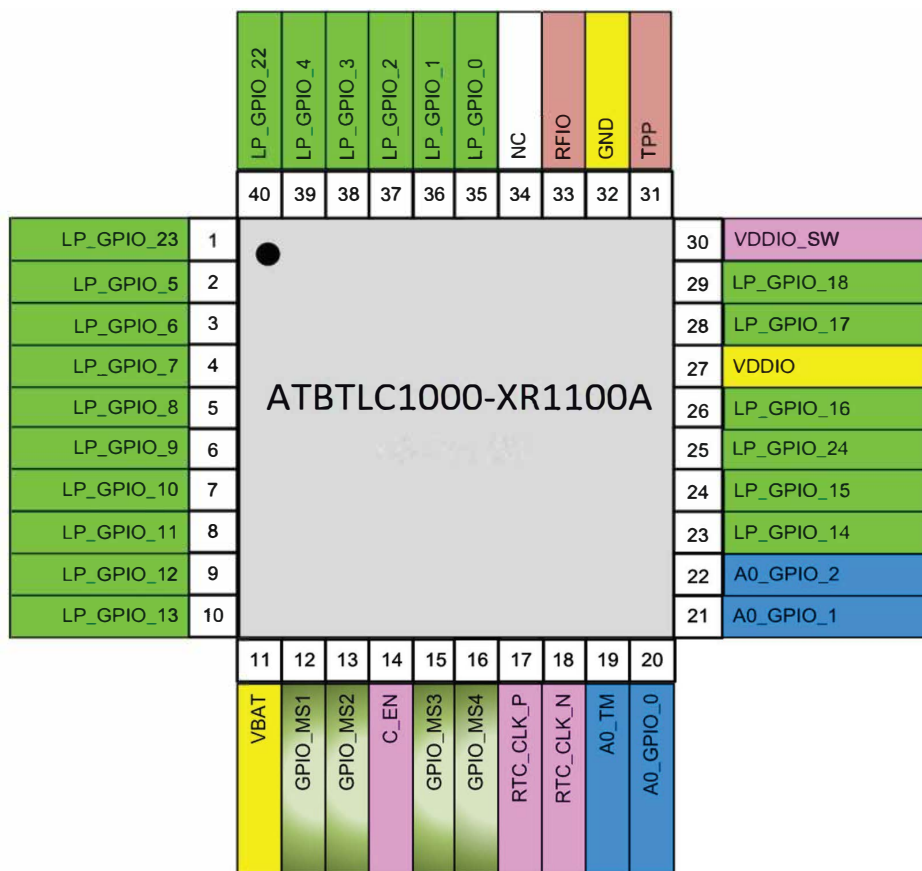
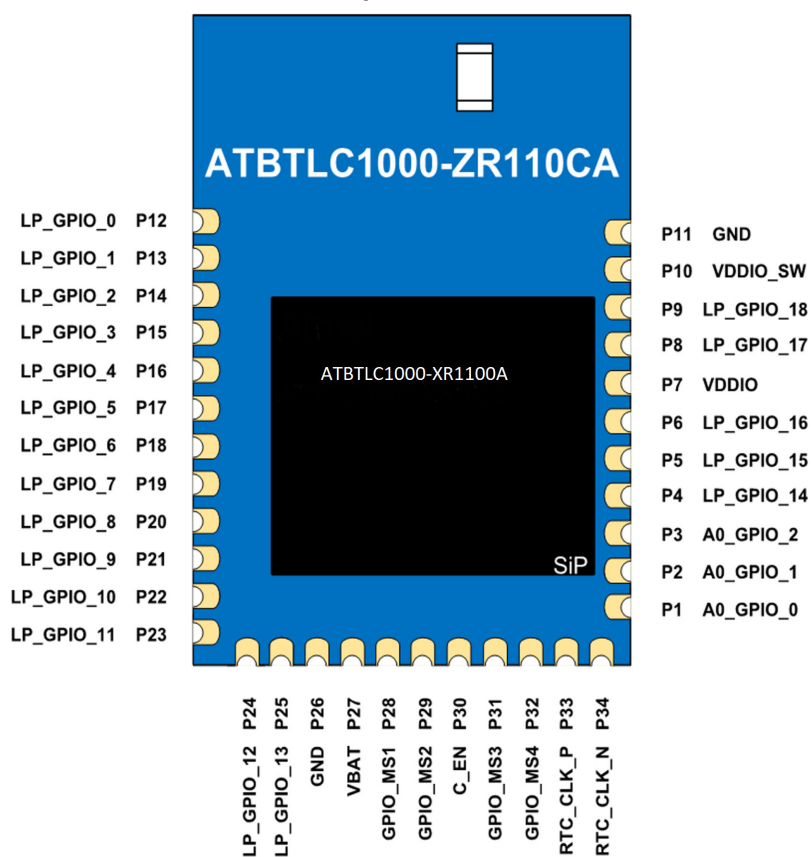


Figure 4-2. ATBTLC1000-ZR110CA Pin Descriptions



The following table lists the pin assignments for both the ATBTLC1000-XR1100A SiP and the ATBTLC1000-ZR110CA module.

Table 4-1. ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA Pin Description

ATBTLC1000-XR1100A Pin #	ATBTLC1000-ZR110CA Pin #	Pin Name	Pin Type	Description / Default Function
1	-	LP_GPIO_23	Digital I/O	GPIO with Programmable Pull Up/Down
2	17	LP_GPIO_5	Digital I/O	GPIO with Programmable Pull Up/Down
3	18	LP_GPIO_6	Digital I/O	GPIO with Programmable Pull Up/Down
4	19	LP_GPIO_7	Digital I/O	GPIO with Programmable Pull Up/Down
5	20	LP_GPIO_8 ⁽¹⁾	Digital I/O	Default function: UART_CTS. To be connected with UART_RTS of host MCU

.....continued

ATBTLC1000- XR1100A Pin #	ATBTLC1000- ZR110CA Pin #	Pin Name	Pin Type	Description / Default Function
6	21	LP_GPIO_9 ⁽¹⁾	Digital I/O	Default function: UART_RTS. To be connected with UART_CTS of host MCU
7	22	LP_GPIO_10	Digital I/O	GPIO with Programmable Pull Up/Down
8	23	LP_GPIO_11	Digital I/O	GPIO with Programmable Pull Up/Down
9	24	LP_GPIO_12	Digital I/O	GPIO with Programmable Pull Up/Down
10	25	LP_GPIO_13	Digital I/O	GPIO with Programmable Pull Up/Down
11	27	VBAT	Power supply	Power supply pin for the DC/DC convertor
12	28	GPIO_MS1	Mixed Signal I/O	GPIO with Programmable Pull Up/ Down. Default function in BluSDK: Host wake-up ⁽²⁾
13	29	GPIO_MS2	Mixed Signal I/O	GPIO with Programmable Pull Up/Down
14	30	C_EN	Digital Input	Can be used to control the state of PMU. High-level enables the module; low-level places module in power-down mode. Connect to a host output that defaults low at power up. If the host output is tri-stated, add a 1 MOhm pull down resistor to ensure a low-level at power-up
15	31	GPIO_MS3	Mixed Signal I/O	GPIO with Programmable Pull Up/Down
16	32	GPIO_MS4	Mixed Signal I/O	GPIO with Programmable Pull Up/Down
17	33	RTC_CLK_P	Analog	Crystal pin or External clock supply, see 7.3 32.768 kHz RTC Crystal Oscillator (RTC XO)

.....continued

ATBTLC1000- XR1100A Pin #	ATBTLC1000- ZR110CA Pin #	Pin Name	Pin Type	Description / Default Function
18	34	RTC_CLK_N	Analog	Crystal pin, see 7.3 32.768 kHz RTC Crystal Oscillator (RTC XO)
19	-	AO_TM	Digital Input	Always On Test Mode. Connect to GND
20	1	AO_GPIO_0	Always On Digital I/O, Programmable Pull Up/Down	Can be used to wake-up the device from Ultra_Low_Power mode by the host MCU
21	2	AO_GPIO_1	Always On. Digital I/O	GPIO with Programmable Pull Up/Down
22	3	AO_GPIO_2	Always On. Digital I/O	GPIO with Programmable Pull Up/Down
23	4	LP_GPIO_14	Digital I/O	GPIO with Programmable Pull Up/Down
24	5	LP_GPIO_15	Digital I/O	GPIO with Programmable Pull Up/Down
25	-	LP_GPIO_24	Digital I/O	GPIO with Programmable Pull Up/Down
26	6	LP_GPIO_16	Digital I/O	GPIO with Programmable Pull Up/Down
27	7	VDDIO	Power supply	Power supply pin for the I/O pins. Can be less than or equal to voltage supplied at VBAT
28	8	LP_GPIO_17	Digital I/O	GPIO with Programmable Pull Up/Down
29	9	LP_GPIO_18	Digital I/O	GPIO with Programmable Pull Up/Down
30	10	VDDIO_SW	DC/DC Power Switch	Do not connect
31	-	TPP		Do not connect
32	11, 26	GND	Ground	
33	-	RFIO	Analog I/O	RX input and TX output. Single-ended RF I/O; To be connected to antenna
34	-	NC		Do not connect

.....continued

ATBTLC1000- XR1100A Pin #	ATBTLC1000- ZR110CA Pin #	Pin Name	Pin Type	Description / Default Function
35	12	LP_GPIO_0	Digital I/O	SWD clock
36	13	LP_GPIO_1	Digital I/O	SWD I/O
37	14	LP_GPIO_2	Digital I/O	Default function: UART_RXD. To be connected with UART_TXD of host MCU
38	15	LP_GPIO_3	Digital I/O	Default function: UART_TXD. To be connected with UART_RXD of host MCU
39	16	LP_GPIO_4	Digital I/O	GPIO with Programmable Pull Up/Down
40	-	LP_GPIO_22	Digital I/O	GPIO with Programmable Pull Up/Down
41-49	35	Paddle	Ground	Exposed paddle must be soldered to system ground

Note:

1. These GPIO pads are high-drive pads. Refer to [Table 11-3](#).
2. Refer [6. Host Microcontroller Interface](#).

5. Device States

This section provides a description of and information about controlling the device states.

5.1 Description of Device States

The ATBTLC1000-XR1100A and the ATBTLC1000-ZR110CA have multiple device states, depending on the state of the ARM processor and BLE subsystem.

Note: The ARM is required to be powered on if the BLE subsystem is active.

- BLE_On_Transmit – Device is actively transmitting a BLE signal (Irrespective of whether ARM processor is active or not)
- BLE_On_Receive – Device is actively receiving a BLE signal (Irrespective of whether ARM processor is active or not)
- Ultra_Low_Power – BLE subsystem and ARM processor are powered-down (with or without RAM retention)
- Power_Down – Device core supply off

5.1.1 Controlling the Device States

The following pins are used to switch between the main device states:

- C_EN – used to enable PMU
- VDDIO – I/O supply voltage from an external power supply
- AO_GPIO_0 - can be used to control the device from entering/exiting Ultra_Low_Power mode

To be in the Power_Down state, the VDDIO supply must be turned on and the C_EN must be maintained at logic low (at GND level). To exit from the Power_Down state, C_EN must change between logic low and logic high (VDDIO voltage level). Once the device is out of the Power_Down state, all other state transitions are controlled by software. When VDDIO supply is turned off and C_EN is in logic low, the chip is powered off with no leakage.

When VDDIO supply is turned off, voltage cannot be applied to the ATBTLC1000-XR1100A pins, as each pin contains an ESD diode from the pin to supply. This diode turns on when a voltage higher than one diode-drop is supplied to the pin.

If voltage is to be applied to the signal pads while the chip is in a low-power state, the VDDIO supply must be on, so that the Power_Down state is used. Similarly, to prevent the pin-to-ground diode from turning on, do not apply a voltage to any pin that is more than one diode-drop below ground.

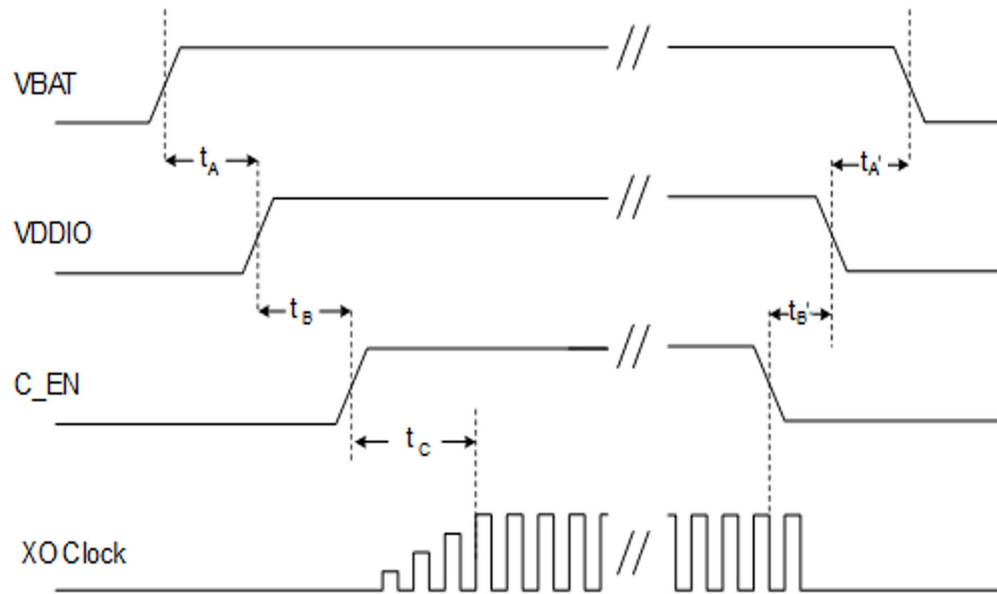
The AO_GPIO_0 pin can be used to control the device from entering and exiting Ultra_Low_Power mode. When AO_GPIO_0 is maintained in logic high state, the device will not enter Ultra_Low_Power mode. When the AO_GPIO_0 is maintained in logic low, the device will enter Ultra_Low_Power mode provided there are no BLE events to be handled.

For more details on how sleep and wake-up are handled, refer to the ATSAMB11 BluSDK Smart Interrupts and ULP Architecture and Usage User guide.

5.2 Power-up/Power-down Sequence

The power sequences and timing parameters for the ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA, are illustrated below.

Figure 5-1. Power-up/Power-down Sequence



The timing parameters are provided in the following table.

Table 5-1. Power-up/Power-down Sequence Timing

Parameter	Min.	Max.	Units	Description	Notes
t_A	0		ms	VBAT rise to VDDIO rise	VBAT and VDDIO can rise simultaneously or can be tied together
t_B	0			VDDIO rise to C_EN rise	C_EN must not rise before VDDIO. C_EN must be driven high or low, not left floating.
t_C	10		μ s	C_EN rise to 31.25 kHz (2 MHz/64) oscillator stabilizing	
$t_{B'}$	0		ms	C_EN fall to VDDIO fall	C_EN must fall before VDDIO. C_EN must be driven high or low, not left floating.
$t_{A'}$	0			VDDIO fall to VBAT fall	VBAT and VDDIO can fall simultaneously or be tied together

5.3 Digital and Mixed-Signal I/O Pin Behavior during Power-Up Sequences

The following table represents I/O pin states corresponding to device power modes.

Table 5-2. I/O Pin Behavior in the Different Device States ⁽¹⁾

Device State	VDDIO	CHIP_EN	Output Driver	Input Driver	Pull Up/Down Resistor ⁽²⁾
Power_Down: core supply off	High	Low	Disabled (Hi-Z)	Disabled	Disabled
Power-on Reset: core supply on, POR hard reset pulse on	High	High	Disabled (Hi-Z)	Disabled	Disabled ⁽³⁾
Power-on Default: core supply on, device out of reset, but not programmed yet	High	High	Disabled (Hi-Z)	Enabled ⁽⁴⁾	Enabled Pull Up ⁽⁴⁾
BLE_On: core supply on, device programmed by firmware	High	High	Programmed by firmware for each pin: Enabled or Disabled (Hi-Z) ⁽⁵⁾ , when Enabled driving 0 or 1	Opposite of Output Driver state: Disabled or Enabled ⁽⁵⁾	Programmed by firmware for each pin: Enabled or Disabled, Pull Up or Pull Down ⁽⁵⁾
Ultra_Low_Power: core supply on for always-on domain, core supply off for switchable domains	High	High	Retains previous state ⁽⁶⁾ for each pin: Enabled or Disabled (Hi-Z), when Enabled driving 0 or 1	Opposite of Output Driver state: Disabled or Enabled ⁽⁵⁾	Retains previous state ⁽⁶⁾ for each pin: Enabled or Disabled, Pull Up or Pull Down

Note:

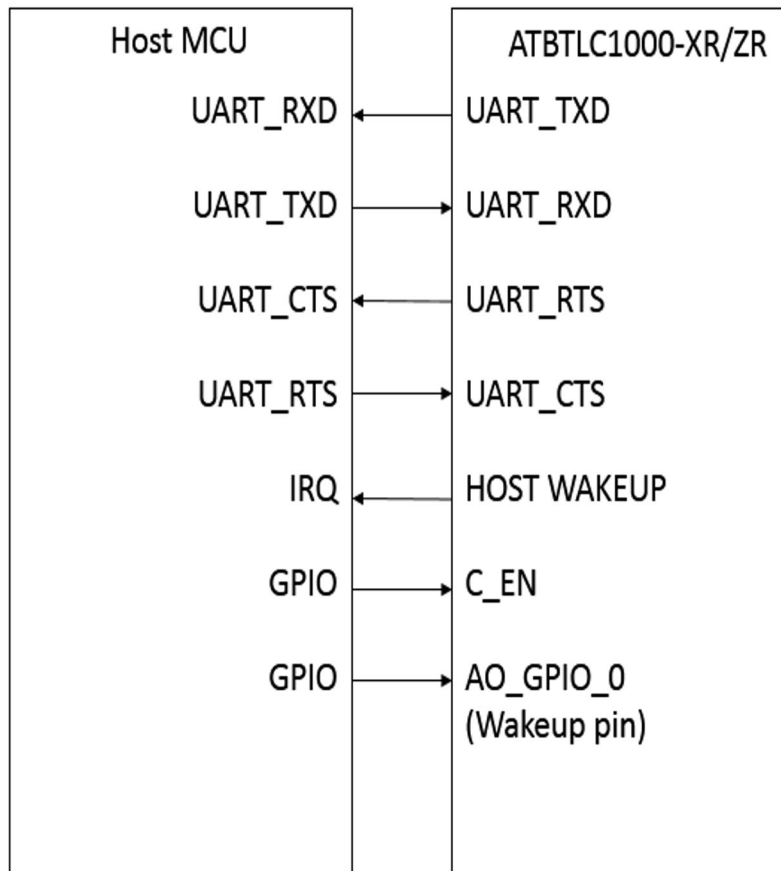
1. This table applies to all three types of I/O pins (digital switchable domain GPIOs, digital always-on/wake-up GPIO, and mixed-signal GPIOs) unless otherwise noted.
2. Pull up/down resistor value is 96 kOhm $\pm 10\%$.
3. In Power-on Reset state, the pull up resistor is enabled in the always-on/wake-up GPIO only.
4. In Power-on Default state, the input drivers and pull up/down resistors are disabled in the mixed-signal GPIOs only (mixed-signal GPIOs are defaulted to analog mode, see the note below).
5. Mixed-signal GPIOs can be programmed to be in analog or digital mode for each pin: when programmed to analog mode (default), the output driver, input driver, and pull up/down resistors are all disabled.
6. In Ultra_Low_Power state, the always-on/wake-up GPIO does not have retention capability and behaves same as in MCU_Only or BLE_On states, also for mixed-signal GPIOs programming analog mode overrides retention functionality for each pin.

6. Host Microcontroller Interface

This section describes the interface of ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA with the host MCU. The interface to be used is UART with hardware flow control. It requires two additional GPIOs and one interrupt pin from the host MCU.

The following figure shows the details of the ATBTLC1000-XR/ZR Host Microcontroller Interface.

Figure 6-1. Host Microcontroller to ATBTLC1000-XR/ZR Interface



The host wake-up pin from ATBTLC1000 can be connected to any interrupt pin of the host MCU. The host MCU can monitor this pin level and decide to wake-up based on events from ATBTLC1000.

The host wake-up pin will be held in logic high ('1') by default and at conditions, where there is no pending event data in the ATBTLC1000. The host wake-up pin will be held in logic low ('0'), when there is event data available from ATBTLC1000 and the pin will be held in this state until all event data is sent out from ATBTLC1000. By default in BluSDK, GPIO_MS1 is used as the host wake-up pin. For more details on available options to re-configure the host wake-up pin from ATBTLC1000, refer to release notes and API user manual documents available in the BluSDK release package.

The UART configurations to be used are as follows:

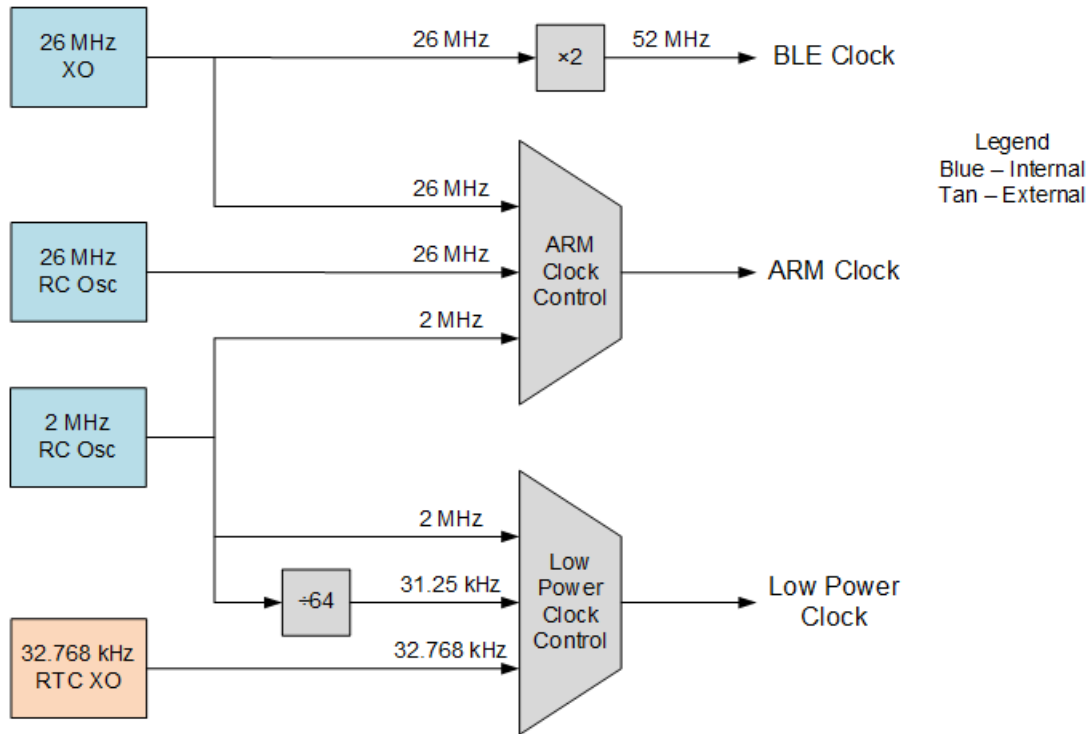
- Baud rate: Configurable in the BluSDK during initialization. For more details, refer to release notes and API user manual documents, available in the ATBTLC1000 BluSDK Release Package.
- Parity: None
- Stop bits: 1

- Data size: 8 bits

7. Clocking

7.1 Overview

Figure 7-1. Clock Architecture



[Clock Architecture](#) provides an overview of the clock tree and clock management blocks.

The BLE Clock is used to drive the BLE subsystem. The ARM clock is used to drive the Cortex-M0 MCU and its interfaces (UART, SPI, and I²C); the recommended MCU clock speed is 26 MHz. The low power clock is used to drive all the low power applications like the BLE sleep timer, always-on power sequencer, always-on timer, and others.

The 26 MHz integrated RC Oscillator is used for most general purpose operations on the MCU and its peripherals. In cases when the BLE subsystem is not used, the RC oscillator can be used for low power consumption. The frequency variation of this RC oscillator and 2 MHz integrated RC Oscillator are up to $\pm 50\%$ over process, voltage, and temperature.

The 32.768 kHz RTC Crystal Oscillator (RTC XO) is used for BLE operations, as it reduces power consumption by providing the best timing for wake-up precision, which allows the circuits to be in low power sleep mode for as long as possible, until they need to wake-up and connect during the BLE connection event.

7.2 26 MHz Crystal Oscillator (XO)

A 26 MHz crystal oscillator is integrated into the ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA to provide the precision clock for the BLE operations.

7.3 32.768 kHz RTC Crystal Oscillator (RTC XO)

7.3.1 General Information

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA contain a 32.768 kHz RTC oscillator that is used for Bluetooth Low Energy activities involving connection events. To be compliant with the BLE specifications for connection events, the frequency accuracy of this clock has to be within ± 500 ppm. Because of the high accuracy of the 32.768 kHz crystal oscillator clock, the power consumption can be minimized by leaving radio circuits in low-power Sleep mode for as long as possible, until they need to wake up for the next connection timed event.

The block diagram in [Figure\(a\)](#) illustrates how the internal low frequency Crystal Oscillator (XO) is connected to the external crystal.

The RTC XO contains:

- Programmable internal capacitance with a maximum of 15 pF on each terminal
- RTC_CLK_P
- RTC_CLK_N

When bypassing the crystal oscillator with an external signal, the user can program down the internal capacitance to its minimum value (~ 1 pF) for easier driving capability. The driving signal is applied to the RTC_CLK_P terminal, as illustrated in [Figure \(b\)](#).

The need for external bypass capacitors depends on the chosen crystal characteristics. Typically, the crystal must be chosen with a load capacitance of 7 pF to minimize the oscillator current. Refer to the data sheet of the preferred crystal and take into account the on-chip capacitance.

Alternatively, if an external 32.768 kHz clock is available, it can be used to drive the RTC_CLK_P pin, instead of using a crystal. The XO contains 6 pF internal capacitance on the RTC_CLK_P pin. To bypass the crystal oscillator, an external signal capable of driving 6 pF can be applied to the RTC_CLK_P terminal, as illustrated in [Figure \(b\)](#). RTC_CLK_N must be left unconnected when driving an external source into RTC_CLK_P. Refer to the [Table 7-1](#) for the specification of the external clock to be supplied at RTC_CLK_P.

Figure 7-2. Connections to RTC XO

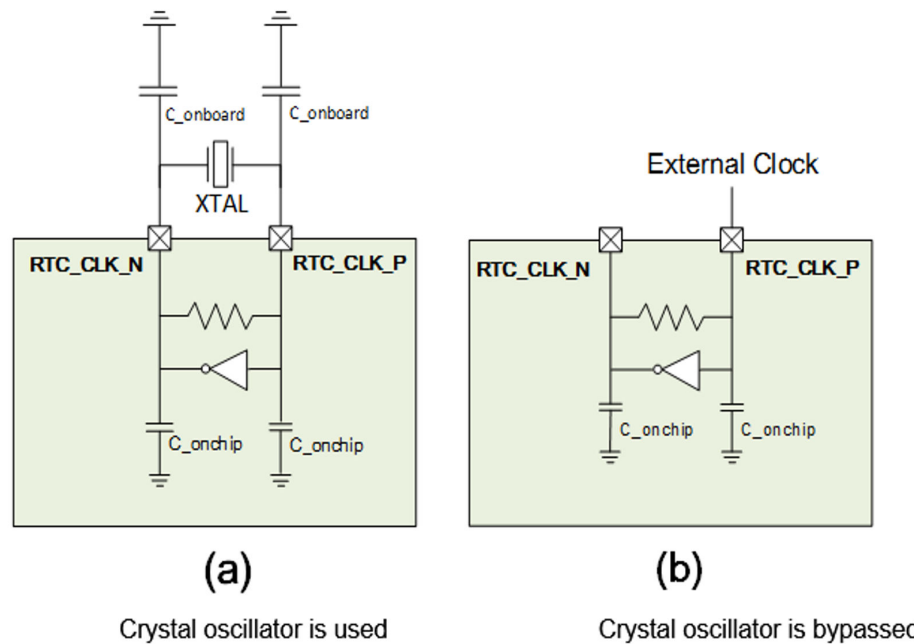


Table 7-1. 32.768 kHz External Clock Specification

Parameter	Min.	Typ.	Max	Unit	Comments
Oscillation frequency		32.768		kHz	Must be able to drive 6 pF load at desired frequency
VinH	0.7		1.2	V	High-level input voltage
VinL	0		0.2		Low-level input voltage
Stability – Temperature	-250		+250	ppm	

Additional internal trimming capacitors (C_onchip) are available. They provide the possibility to tune the frequency output of RTC XO without changing the external load capacitors.

Note:

Refer the BluSDK BLE API Software Development Guide for details on how to enable the 32.768 kHz clock output and tune the internal trimming capacitors.

Table 7-2. 32.768 kHz XTAL C_onchip Programming

Register: pierce_cap_ctrl[3:0]	C_onchip [pF]
0000	0.0
0001	1.0
0010	2.0
0011	3.0
0100	4.0
0101	5.0
0110	6.0

.....continued	
Register: pierce_cap_ctrl[3:0]	C_onchip [pF]
0111	7.0
1000	8.0
1001	9.0
1010	10.0
1011	11.0
1100	12.0
1101	13.0
1110	14.0
1111	15.0

7.3.2 RTC XO Design and Interface Specification

The RTC consists of two main blocks: the Programmable Gm stage and tuning capacitors. The programmable Gm stage is used to guarantee start-up and to sustain oscillation. Tuning capacitors are used to adjust the XO center frequency and control the XO precision for different crystal models. The output of the XO is driven to the digital domain through a digital buffer stage with a supply voltage of 1.2V.

Table 7-3. RTC XO Interface

Pin Name	Function	Register Default
Digital Control Pins		
Pierce_res_ctrl	Control feedback resistance value: 0 = 20 MOhm Feedback resistance 1 = 30 MOhm Feedback resistance	0X4000F404<15>='1'
Pierce_cap_ctrl<3:0>	Control the internal tuning capacitors with step of 700 fF: 0000=700 fF 1111=11.2 pF Refer to crystal datasheet to check for optimum tuning capacitance value	0X4000F404<23:20>="1000"
Pierce_gm_ctrl<3:0>	Controls the Gm stage gain for different crystal mode: 0011= for crystal with shunt capacitance of 1.2 pF 1000= for crystal with shunt capacitance of >3 pF	0X4000F404<19:16>="1000"
VDD_XO	1.2V	

7.3.3 RTC Characterization with Gm Code Variation at Supply 1.2V and Temp. = 25°C

This section shows the RTC total drawn current and the XO accuracy versus different tuning capacitors and different GM codes, at a supply voltage of 1.2V and temperature = 25°C.

Figure 7-3. RTC Drawn Current vs. Tuning Caps at 25°C

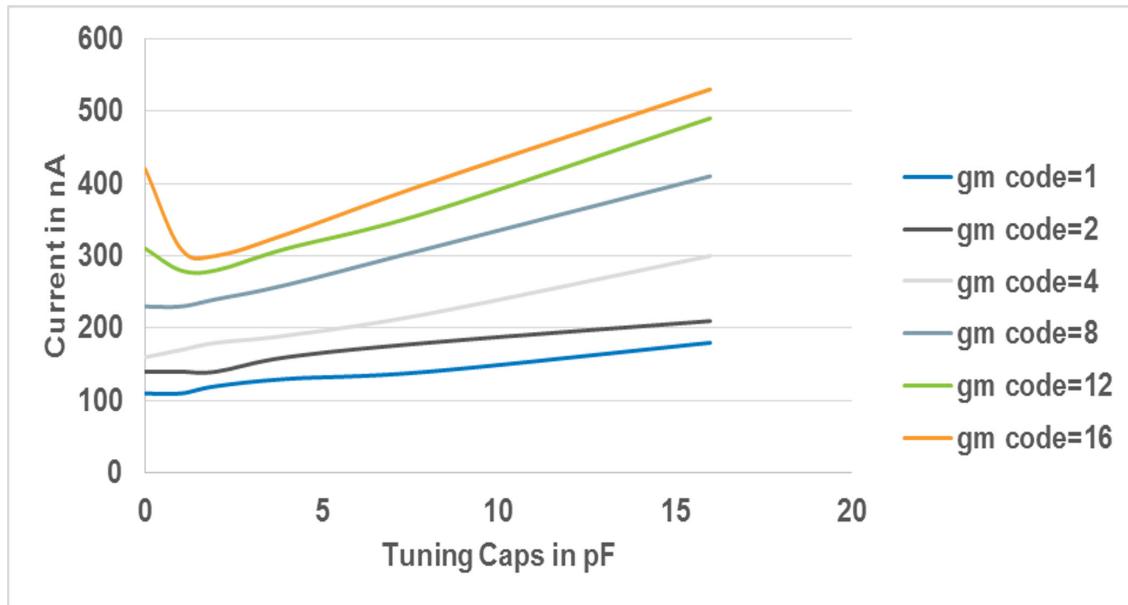
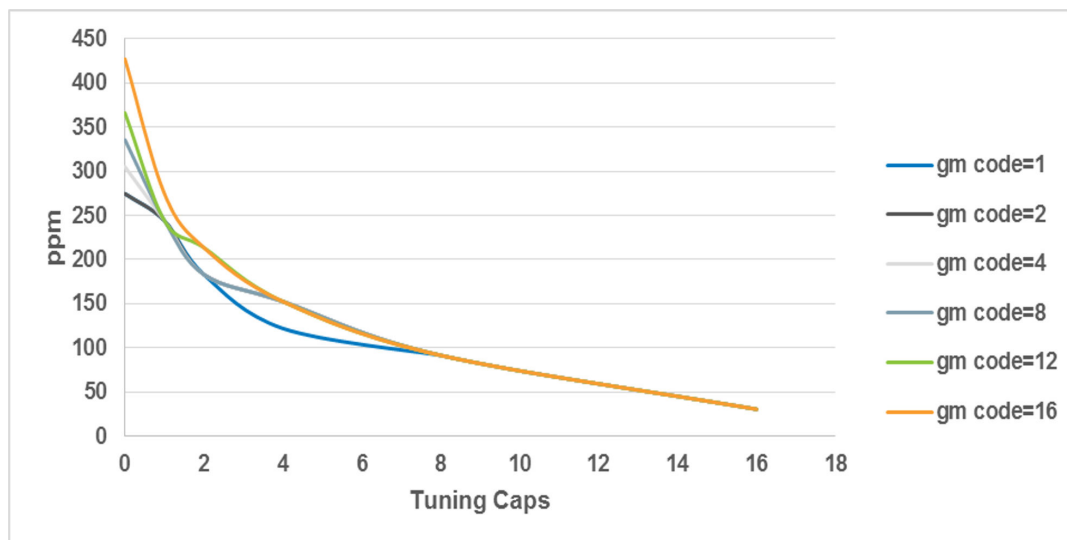


Figure 7-4. RTC Oscillation Frequency Deviation vs. Tuning Caps at 25°C



7.3.4 RTC Characterization with Supply Variation and Temp. = 25°C

Figure 7-5. RTC Drawn Current vs. Supply Variation

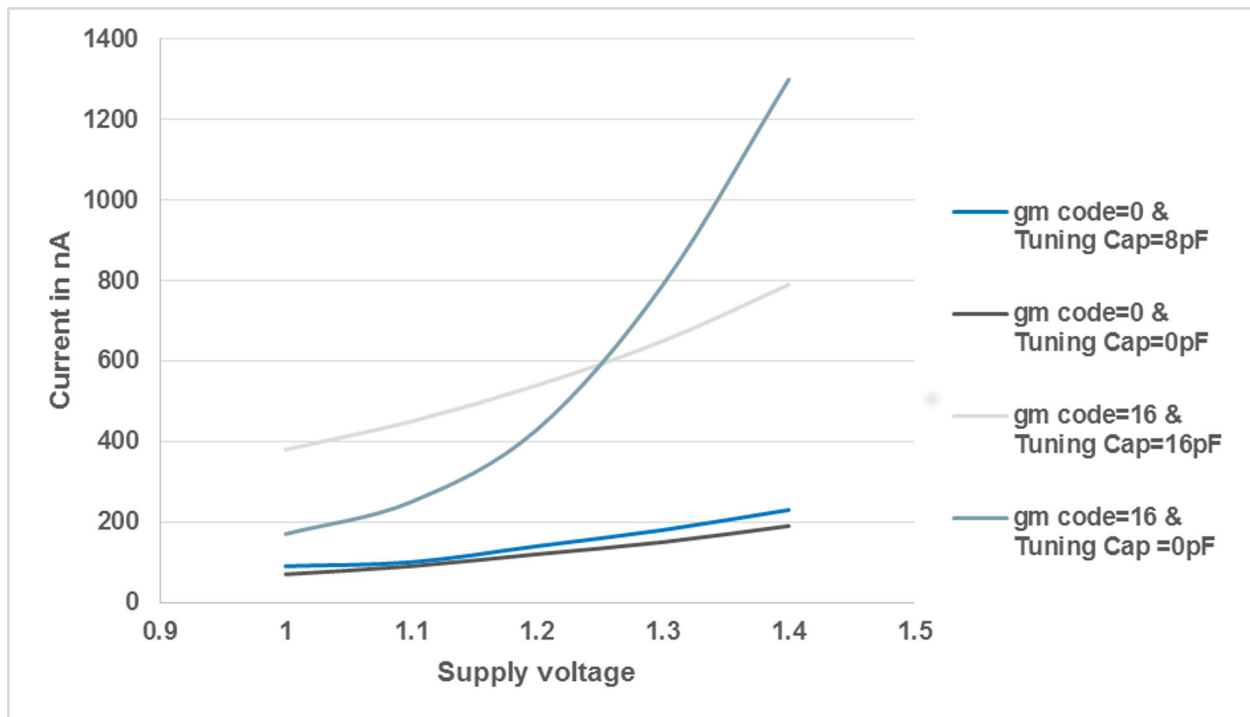
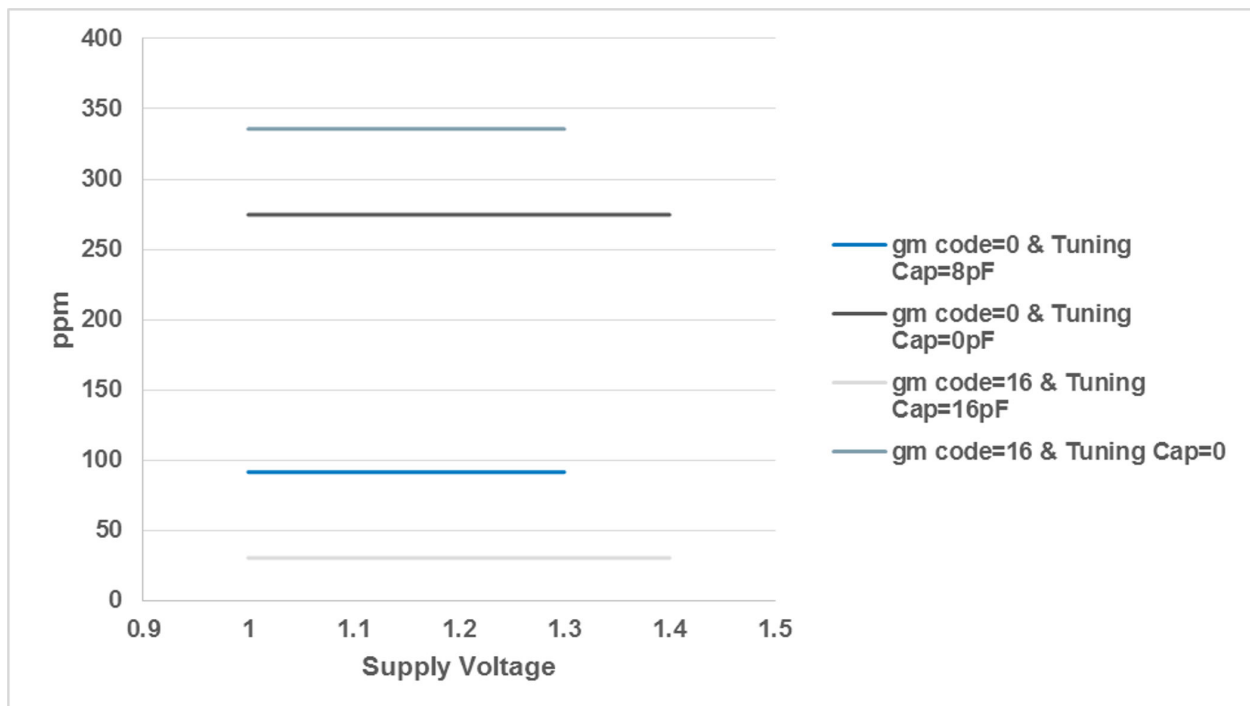


Figure 7-6. RTC Frequency Deviation vs. Supply Voltage



7.4 2 MHz Integrated RC Oscillator

The 2 MHz integrated RC Oscillator circuit without calibration contains a frequency variation of 50% over process, temperature, and voltage variation. As described above, calibration over process, temperature, and voltage are required to maintain the accuracy of this clock.

Figure 7-7. 32 kHz RC Oscillator PPM Variation vs. Calibration Time at Room Temperature

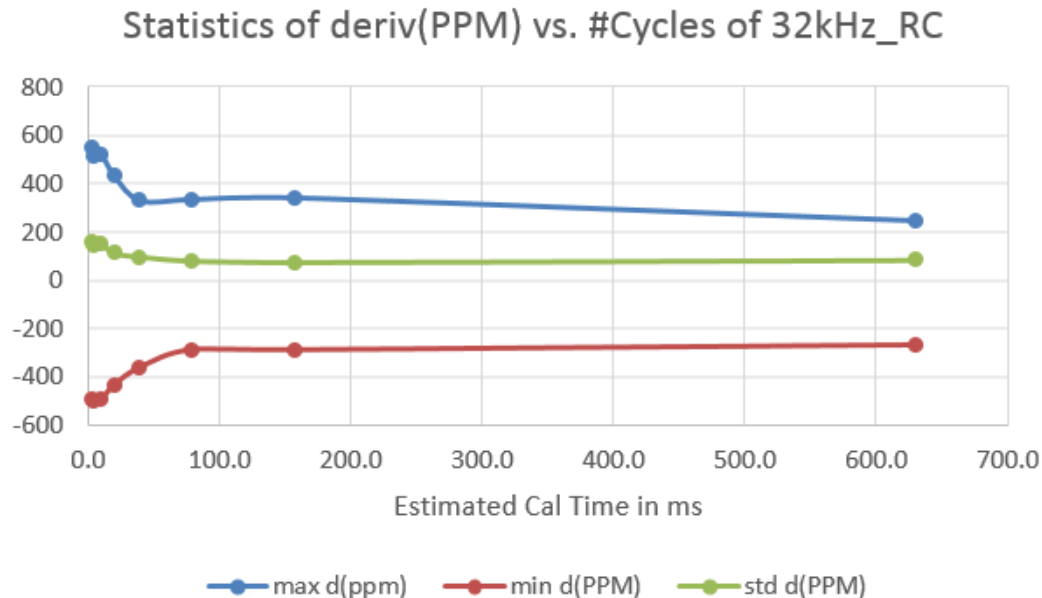
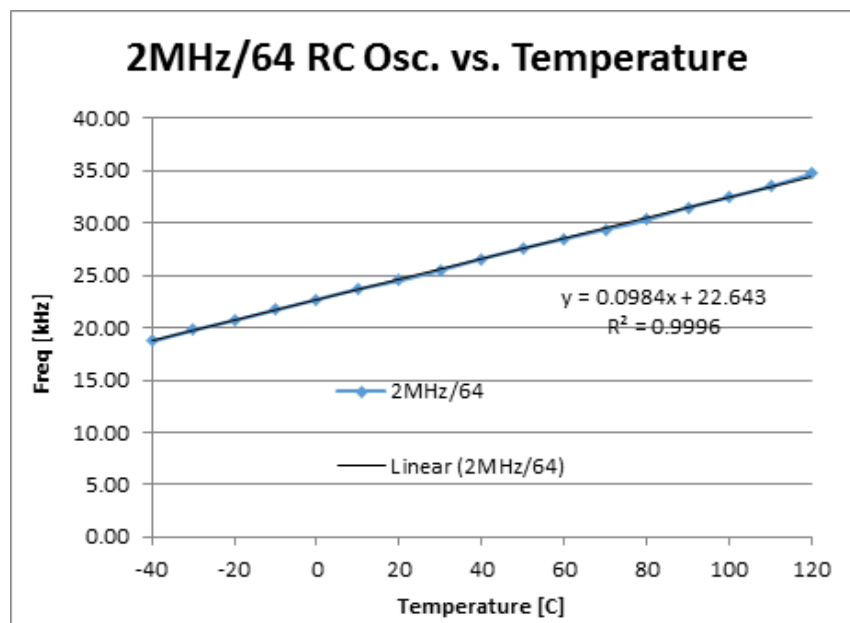


Figure 7-8. 32 kHz RC Oscillator Frequency Variation over Temperature



8. CPU and Memory Subsystem

8.1 ARM Subsystem

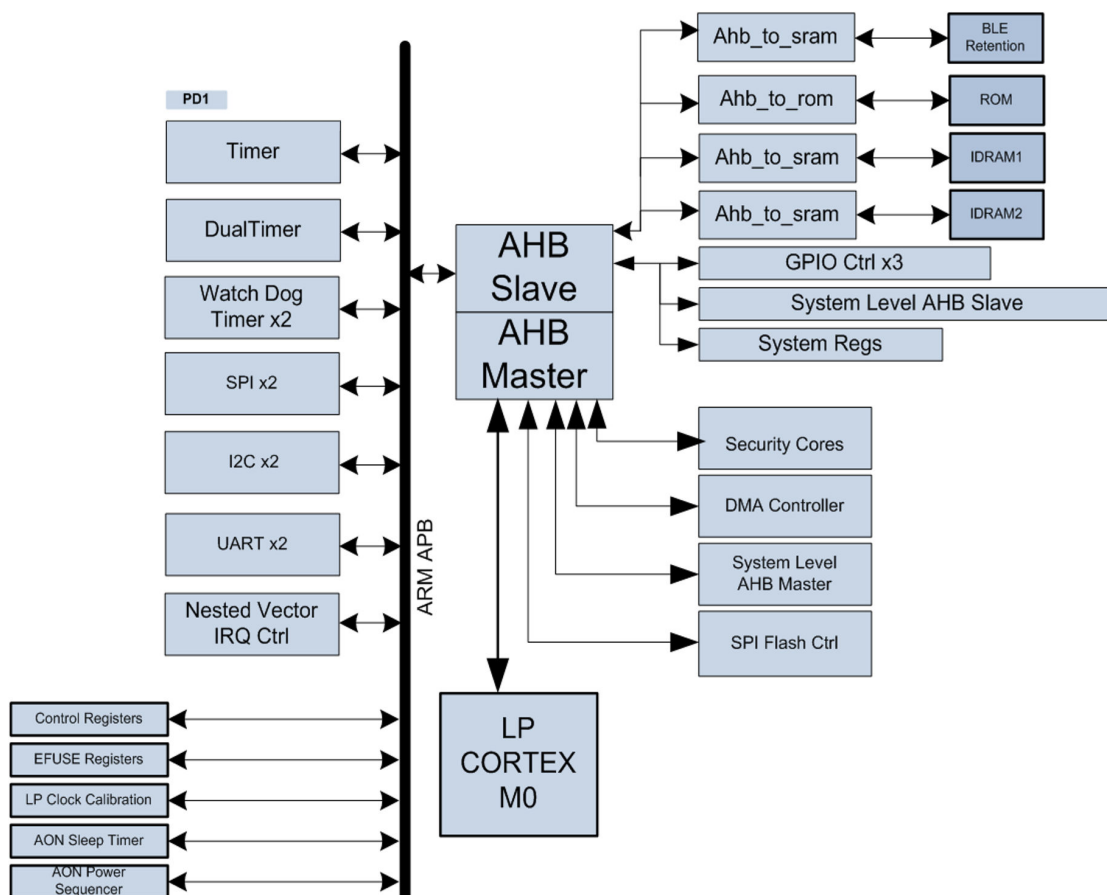
The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have an ARM Cortex-M0 32-bit processor. It is responsible for controlling the BLE subsystem and handling all application features.

The Cortex-M0 microcontroller consists of a full 32-bit processor capable of addressing 4 GB of memory. It has a RISC like load/store instruction set and internal 3-stage Pipeline Von Neumann architecture.

The Cortex-M0 processor provides a single system level interface using AMBA technology to provide high speed and low latency memory accesses.

The Cortex-M0 processor implements a complete hardware debug solution with four hardware breakpoint and two watchpoint options. This provides high system visibility of the processor, memory, and peripherals through a 2-pin Serial Wire Debug (SWD) port that is ideal for microcontrollers and other small package devices.

Figure 8-1. ARM Cortex-M0 Subsystem



8.1.1 Features

The processor features and benefits are:

- Tight integration with the system peripherals to reduce area and development costs

- Thumb instruction set combines high code density with 32-bit performance
- Integrated sleep modes using a wake-up interrupt controller for low power consumption
- Deterministic and high performance interrupt handling through nested vector interrupt controller for time-critical applications
- Serial Wire Debug reduces the number of pins required for debugging
- DMA engine for Peripheral-to-Memory, Memory-to-Memory, and Memory-to-Peripheral operation

8.1.2 ARM Module Descriptions

8.1.2.1 Timer

The 32-bit timer block allows the CPU to generate a time tick at a programmed interval. This feature can be used for a wide variety of functions, such as counting, interrupt generation and time tracking.

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.2 Dual Timer

The APB dual-input timer module is an APB slave module consisting of two programmable 32-bit down-counters that can generate interrupts, when they expire. The timer can be used in a Free-running, Periodic, or One-shot mode.

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.3 Watchdog Timer

The two watchdog blocks allow the CPU to be interrupted, if it has not interacted with the watchdog timer before it expires. In addition, this interrupt will be an output of the core, so that it can be used to reset the CPU in the event that a direct interrupt to the CPU is not useful. This allows the CPU to get back to a known state in the event a program is no longer executing as expected. The watchdog module applies a reset to a system in the event of a software failure, providing a way to recover from software crashes.

The watchdog timer is used by the BLE stack; it cannot be used by user application.

8.1.2.4 Wake-up timer

This timer is a 32-bit countdown timer that operates on the 32 kHz sleep clock. It can be used as a general-purpose timer for the ARM or as a wake-up source for the chip. It has the ability to be a one-time programmable timer, as it will generate an interrupt/wake-up on expiration and stop operation. It also has the ability to be programmed in an auto reload fashion, where it will generate an interrupt/wake-up and then proceed to start another countdown sequence.

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.5 SPI Controller

See [SPI Master/Slave Interface](#).

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.6 I²C Controller

See [I²C Master/Slave Interface](#).

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.7 UART

See [UART Interface](#).

Note: Accessing and controlling the registers of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.8 DMA Controller

Direct Memory Access (DMA) allows certain hardware subsystems to access main system memory independent of the Cortex-M0 Processor.

The DMA features and benefits are as follows:

- Supports any address alignment
- Supports any buffer size alignment
- Peripheral flow control and peripheral block transfer
- The following modes are supported:
 - Peripheral to peripheral transfer
 - Memory to memory
 - Memory to peripheral
 - Peripheral to memory
 - Register to memory
- Interrupts both TX and RX in memory and peripheral modes
- Scheduled transfers
- Endianness byte swapping
- Watchdog timer
- 4-channel operation
- 32-bit data width
- AHB MUX (on read and write buses)
- Command lists support
- Usage of tokens

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.1.2.9 Nested Vector Interrupt Controller (NVIC)

External interrupt signals connect to the NVIC, and the NVIC prioritizes the interrupts. Software can set the priority of each interrupt. The NVIC and the Cortex-M0 processor core are closely coupled, providing low latency interrupt processing and efficient processing of late arriving interrupts.

All NVIC registers are accessible through word transfers and are little endian. Any attempt to read or write a half-word or byte individually is unpredictable.

The NVIC allows the CPU to be able to individually enable and disable each interrupt source, and hold each interrupt until it is serviced and cleared by the CPU.

Table 8-1. NVIC Register Summary

Name	Description
ISER	Interrupt Set-Enable Register
ICER	Interrupt Clear-Enable Register

.....continued	
Name	Description
ISPR	Interrupt Set-Pending Register
ICPR	Interrupt Clear-Pending Register
IPR0-IPR7	Interrupt Priority Registers

Note: For a description of each register, see the Cortex-M0 documentation from ARM.

8.1.2.10 GPIO Controller

The AHB GPIO is a general-purpose I/O interface unit that allows the CPU to independently control all input or output signals on the ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA. These can be used for a wide variety of functions pertaining to the application.

The AHB GPIO provides a 16-bit I/O interface with the following features:

- Programmable interrupt generation capability
- Programmable masking support
- Thread-safe operation by providing separate set and clear addresses for control registers
- Inputs are sampled using a double flip-flop to avoid meta-stability issues

Note: Usage of this peripheral is not supported by the SDK. The datasheet will be updated once the support for this feature is added in SDK.

8.2 Memory Subsystem

The Cortex-M0 core uses a 128 KB instruction/boot ROM along with a 128 KB shared instruction and data RAM.

8.2.1 Shared Instruction and Data Memory

The Instruction and Data Memory (IDRAM1 and IDRAM2) contains instructions and data used by the ARM. The 128 KB size of IDRAM1 and IDRAM2 is used for the BLE subsystem. IDRAM1 contains three 32 KB memories and IDRAM2 contains two 16 KB memories that are accessible to the ARM and used for instruction/data storage.

8.2.2 ROM

The ROM is used to store the boot code and BLE firmware, stack, and selected user profiles. The ROM contains the 128 KB memory that is accessible to the ARM.

8.2.3 BLE Retention Memory

The BLE functionality requires 8 KB state, instruction, and data to be retained in memory, when the processor either goes into Sleep mode or Power Off mode. The RAM is separated into specific power domains to allow tradeoff in power consumption with retention memory size.

8.3 Non-Volatile Memory

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have 768 bits of non-volatile eFuse memory that can be read by the CPU after device reset. This memory region is one-time-programmable. It is partitioned into six 128-bit banks. Each bank is divided into four blocks with each block containing 32 bits

of memory locations. This non-volatile, one-time-programmable memory is used to store customer specific parameters as listed below.

- 26 MHz XO calibration information
- UART hardware flow control pin selection
- BT address

The bit map for the block containing the above parameters is detailed in the following figures.

Figure 8-2. Bank 5 Block 0

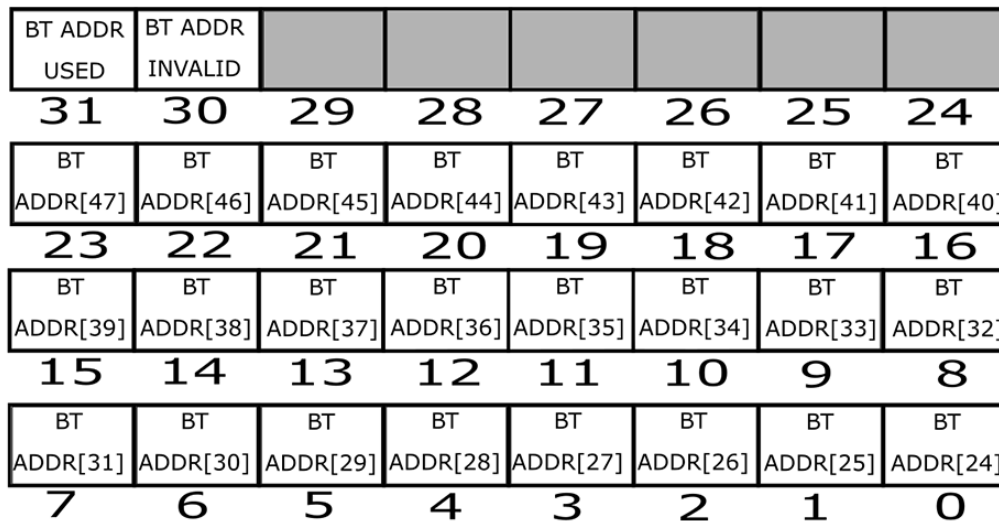


Figure 8-3. Bank 5 Block 1

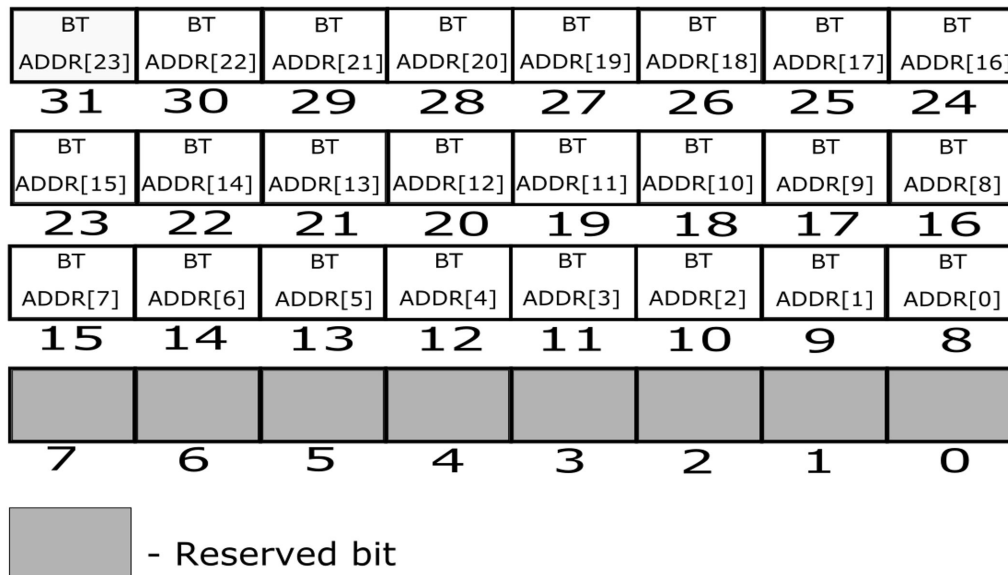
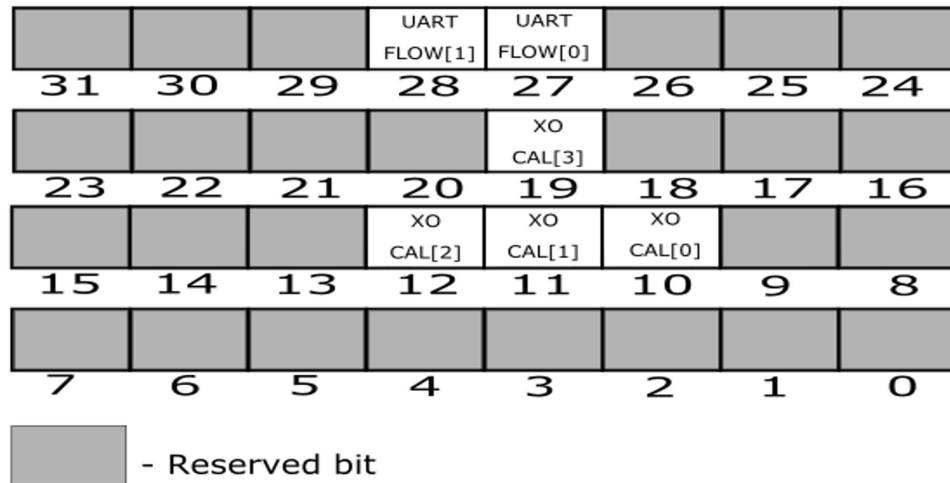


Figure 8-4. Bank 5 Block 3



The bits that are not depicted in the above register description are all reserved for future use.

8.3.1 26 MHz XO Calibration information

Information for both ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA are pre-programmed. The user does not need to reconfigure them.

8.3.2 UART Hardware Flow Control Pin Selection

These bits determine the LP_GPIO pins to be used as the hardware flow control pins (RTS and CTS) of the UART interface with host MCU. For both ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA, these bits will have a default value of 0b10. Possible values for these bits and the corresponding configuration are shown below.

Table 8-2. UART Flow Control Bank 5 Block 3

UART Flow control Bank 5 Block 3[28:27]	UART RTS	UART CTS
0b10	LP_GPIO_9	LP_GPIO_8
0b11	LP_GPIO_5	LP_GPIO_4

Note: Other values for these bits are reserved.

8.3.3 BT Address

These bits contain the BT address used by the user application. For ATBTLC1000-ZR110CA modules, the BT address is pre-programmed. For ATBTLC1000-XR1100A, the user must purchase the MAC address from IEEE® and store it in the non-volatile memory section of the host MCU. During initialization of ATBTLC1000-XR1100A, the BLE address can be set by the host MCU. Refer to the API User Manual available in the ATBTLC1000 BluSDK Release Package for more details on achieving this.

Bit 31 of Bank 5 Block 0 - BT_ADDR_USED: Programming this bit with a value of 1 indicates that the BT address in the eFuse memory location is intended to be used.

Bit 30 of Bank 5 Block 0 – BT_ADDR_INVALID: Programming this bit with a value of 1 indicates that the BT address in the eFuse memory location is invalid.

9. Bluetooth Low Energy Subsystem

The Bluetooth Low Energy (BLE) subsystem implements all the critical real-time functions required for full compliance with specification of the Bluetooth System v5.0, Bluetooth SIG. It consists of a Bluetooth baseband controller (core), radio transceiver and the Microchip Bluetooth Smart Stack, and the BLE Software Platform.

9.1 BLE Core

The baseband controller consists of a modem and a Medium Access Controller (MAC). It constructs baseband data packages, schedules frames, and manages and monitors connection status, slot usage, data flow, routing, segmentation and buffer control.

The core performs link control layer management supporting the main BLE states, including advertising and connection.

9.1.1 Features

- Broadcaster, Central, Observer, Peripheral
- Simultaneous Master and Slave Operation with up to Eight Connections
- Frequency Hopping
- Advertising/Data/Control packet types
- Encryption (AES-128)
- Bitstream Processing (CRC, whitening)
- 52 MHz Operating Clock

9.2 BLE Radio

The radio consists of a fully integrated transceiver, low noise amplifier, Receive (RX) down converter, analog baseband processing, Phase Locked Loop (PLL), Transmit (TX) Power Amplifier, and Transmit/Receive switch. At the RF front end, no external RF components on the PCB are required other than the antenna and a matching component.

Table 9-1. ATBTLC1000 BLE Radio Features and Properties

Feature	Description
Part Number	ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA
BLE standard	Bluetooth V5.0 – Bluetooth Low Energy
Frequency range	2402 MHz to 2480 MHz
Number of channels	40
Modulation	GFSK
PHY Data rate	1 Mbps

9.3 Microchip BluSDK

BluSDK offers a comprehensive set of tools - including reference applications for several Bluetooth SIG defined profiles and custom profile. This will help the user to quickly evaluate, design and develop BLE products with ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA.

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have a completely integrated Bluetooth Low Energy stack on chip, fully qualified, mature, and Bluetooth V5.0 compliant.

Customer applications interface with the BLE protocol stack through the adaptor library API, which supports direct access to the GAP, SMP, ATT, GATT client / server, and L2CAP service layer protocols in the embedded firmware.

The stack includes numerous BLE profiles for applications like:

- Smart Energy
- Consumer Wellness
- Home Automation
- Security
- Proximity Detection
- Entertainment
- Sports and Fitness
- Key fob

Together with the Atmel Studio Software Development environment, additional customer profiles can be easily developed.

Refer to BluSDK release notes for more details on the supported host MCU architecture and compilers.

9.3.1 Direct Test Mode (DTM) Example Application

A DTM example application is among the reference applications offered in BluSDK. Using this application, the user will be able to configure the device in the different test modes as defined in the Bluetooth Low Energy Core 5.0 specification (Vol6, Part F Direct Test Mode). Please refer the example *Getting Started Guide* available in the BluSDK release package.

10. External Interfaces

10.1 Overview

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA external interfaces include: 2xSPI Master/Slave (SPI0 and SPI1), 2xI²C Master/Slave (I²C0 and I²C1), 2xUART (UART1 and UART2), 1xSPI Flash, 1xSWD, and General Purpose Input/Output (GPIO) pins.



Usage of the above mentioned peripherals is not supported by the SDK. The datasheet will be updated once support is added in SDK. The host interface is UART with flow control and configurations can be found in Section 6. [Host Microcontroller Interface](#).

[Table Pin-MUX Matrix of External Interfaces](#) illustrates the different peripheral functions that are software-selectable for each pin. This allows for maximum flexibility of mapping desired interfaces on GPIO pins. The MUX1 option allows for any MEGAMUX option from [Table Software Selectable MEGAMUX Options](#) to be assigned to a GPIO.

Table 10-1. Pin-MUX Matrix of External Interfaces

Pin Name	XR Pin #	ZR Pin #	Pull	MUX0	MUX1	MUX2	MUX3	MUX4	MUX5	MUX6	MUX7
LP_GPIO_0	35	12	Up/Down	GPIO 0	MEGAMUX 0	SWD CLK					TEST OUT 0
LP_GPIO_1	36	13	Up/Down	GPIO 1	MEGAMUX 1	SWD I/O					TEST OUT 1
LP_GPIO_2	37	14	Up/Down	GPIO 2	MEGAMUX 2	UART1 RXD		SPI1 SCK	SPI0 SCK		TEST OUT 2
LP_GPIO_3	38	15	Up/Down	GPIO 3	MEGAMUX 3	UART1 TXD		SPI1 MOSI	SPI0 MOSI		TEST OUT 3
LP_GPIO_4	39	16	Up/Down	GPIO 4	MEGAMUX 4	UART1 CTS		SPI1 SSN	SPI0 SSN		TEST OUT 4
LP_GPIO_5	2	17	Up/Down	GPIO 5	MEGAMUX 5	UART1 RTS		SPI1 MISO	SPI0 MISO		TEST OUT 5
LP_GPIO_6	3	18	Up/Down	GPIO 6	MEGAMUX 6	UART2 RXD			SPI0 SCK		TEST OUT 6
LP_GPIO_7	4	19	Up/Down	GPIO 7	MEGAMUX 7	UART2 TXD			SPI0 MOSI		TEST OUT 7
LP_GPIO_8	5	20	Up/Down	GPIO 8	MEGAMUX 8	I ² C0 SDA			SPI0 SSN		TEST OUT 8
LP_GPIO_9	6	21	Up/Down	GPIO 9	MEGAMUX 9	I ² C0 SCL			SPI0 MISO		TEST OUT 9

.....continued

Pin Name	XR Pin #	ZR Pin #	Pull	MUX0	MUX1	MUX2	MUX3	MUX4	MUX5	MUX6	MUX7
LP_GPIO_10	7	22	Up/ Down	GPIO 10	MEGAMUX 10	SPI0 SCK					TEST OUT 10
LP_GPIO_11	8	23	Up/ Down	GPIO 11	MEGAMUX 11	SPI0 MOSI					TEST OUT 11
LP_GPIO_12	9	24	Up/ Down	GPIO 12	MEGAMUX 12	SPI0 SSN					TEST OUT 12
LP_GPIO_13	10	25	Up/ Down	GPIO 13	MEGAMUX 13	SPI0 MISO					TEST OUT 13
LP_GPIO_14	23	4	Up/ Down	GPIO 14	MEGAMUX 14	UART2 CTS		I ² C1 SDA			TEST OUT 14
LP_GPIO_15	24	5	Up/ Down	GPIO 15	MEGAMUX 15	UART2 RTS		I ² C1 SLC			TEST OUT 15
LP_GPIO_16	25	6	Up/ Down	GPIO 16	MEGAMUX 16			SPI1 SSN	SPI0 SCK		TEST OUT 16
LP_GPIO_17	28	8	Up/ Down	GPIO 17	MEGAMUX 17			SPI1 SCK	SPI0 MOSI		TEST OUT 17
LP_GPIO_18	29	9	Up/ Down	GPIO 18	MEGAMUX 18			SPI1 MISO	SPI0 SSN		TEST OUT 18
LP_GPIO_22	40		Up/ Down	GPIO 22	MEGAMUX 22						
LP_GPIO_23	1		Up/ Down	GPIO 23	MEGAMUX 23						
AO_GPIO_0	20	1	Up	GPIO 31	WAKEUP	RTC CLK IN	32 KHZ CLK OUT				

.....continued

Pin Name	XR Pin #	ZR Pin #	Pull	MUX0	MUX1	MUX2	MUX3	MUX4	MUX5	MUX6	MUX7
AO_GPIO_1	21	2	Up		WAKEUP	RTC CLK IN	32 kHz CLK OUT				
AO_GPIO_2	22	3	Up		WAKEUP	RTC CLK IN	32 kHz CLK OUT				
GPIO_MS1 (1)	12	17	Up/ Down	GPIO 47							
GPIO_MS2 (1)	13	18	Up/ Down	GPIO 46							
GPIO_MS3 (1)	15	31	Up/ Down	GPIO 45							
GPIO_MS4 (1)	16	32	Up/ Down	GPIO 44							

Note:

1. If analog is selected, the digital is disabled.

[Table Software Selectable MEGAMUX Options](#) provides the various software selectable MEGAMUX options that correspond to specific peripheral functionality.

Table 10-2. Software Selectable MEGAMUX Options

MUX_Sel	Function	Notes
0	UART1 RXD	
1	UART1 TXD	
2	UART1 CTS	
3	UART1 RTS	
4	UART2 RXD	
5	UART2 TXD	
6	UART2 CTS	
7	UART2 RTS	
8	I ² C0 SDA	
9	I ² C0 SCL	
10	I ² C1 SDA	

.....continued		
MUX_Sel	Function	Notes
11	I ² C1 SCL	
12	PWM 1	
13	PWM 2	
14	PWM 3	
15	PWM 4	
16	LP CLOCK OUT	32 kHz clock output (RC Osc. or RTC XO)
17	Reserved	
18	Reserved	
19	Reserved	
20	Reserved	
21	Reserved	
22	Reserved	
23	Reserved	
24	Reserved	
25	Reserved	
26	Reserved	
27	Reserved	
28	Reserved	
29	QUAD DEC X IN A	
30	QUAD DEC X IN B	
31	QUAD DEC Y IN A	
32	QUAD DEC Y IN B	
33	QUAD DEC Z IN A	
34	QUAD DEC Z IN B	

An example of peripheral assignment using these MEGAMUX options is as follows:

- I²C0 pin-MUXed on LP_GPIO_8 and LP_GPIO_9 via MUX1 and MEGAMUX= 8 and 9 ([Table Software Selectable MEGAMUX Options](#))
- I²C1 pin-MUXed on LP_GPIO_14 and LP_GPIO_15 via MUX1 and MEGAMUX= 14 and 15 ([Table Software Selectable MEGAMUX Options](#))
- UART1 pin-MUXed on LP_GPIO_2 and LP_GPIO_3 via MUX1 and MEGAMUX= 2 ([Table Software Selectable MEGAMUX Options](#))

Another example is to illustrate the available options for pin LP_GPIO_3, depending on the pin-MUX option selected:

- MUX0: the pin functions as bit 3 of the GPIO bus and is controlled by the GPIO controller in the ARM subsystem
- MUX1: any option from the MEGAMUX table can be selected, for example, it can be a quad_dec, pwm, or any of the other functions listed in the MEGAMUX table
- MUX2: the pin functions as UART1 TXD; this can be also achieved with the MUX1 option via MEGAMUX, but the MUX2 option allows a shortcut for the recommended pinout
- MUX3: this option is not used and thus defaults to the GPIO option (same as MUX0)
- MUX4: the pin functions as SPI1 MOSI (this option is not available through MEGAMUX)
- MUX5: the pin functions as SPI0 MOSI (this option is not available through MEGAMUX)
- MUX7: the pin functions as bit 3 of the test output bus, giving access to various debug signals

10.2 I²C Master/Slave Interface

10.2.1 Description

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA provides an I²C Interface that can be configured as slave or master. I²C Interface is a two-wire serial interface consisting of a serial data line (SDA) and a serial clock line (SCL). The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA I²C support I²C bus Version 2.1 - 2000 and can operate in the following speed modes:

- Standard (100 kb/s)
- Fast (400 kb/s)
- High-speed (3.4 Mb/s)

The I²C is a synchronous serial interface. The SDA line is a bidirectional signal and changes only while the SCL line is low, except for STOP, START, and RESTART conditions.. The output drivers are open-drain to perform wire-AND functions on the bus. The maximum number of devices on the bus are limited by only the maximum capacitance specification of 400 pF. Data is transmitted in byte packages.

For specific information, refer to the Philips Specification entitled “The I²C -Bus Specification, Ver 2.1”.

10.3 SPI Master/Slave Interface

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA provides a Serial Peripheral Interface (SPI) that can be configured as master or slave. The SPI Interface pins are mapped, as illustrated in the following table. The SPI Interface is a full-duplex slave-synchronous serial interface. When the SPI is not selected, i.e., when SSN is high, the SPI interface will not interfere with data transfers between the serial-master and other serial-slave devices. When the serial slave is not selected, its transmitted data output is buffered, resulting in a high impedance drive onto the serial master receive line. The SPI slave interface responds to a protocol that allows an external host to read or write any register in the chip as well as initiate DMA transfers.

Table 10-3. SPI Interface Pin Mapping

Pin Name	SPI Function
SSN	Active-Low Slave Select
SCK	Serial Clock
MOSI	Master Out Slave In (Data)

.....continued	
Pin Name	SPI Function
MISO	Master In Slave Out (Data)

10.3.1 Description

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA provides a Serial Peripheral Interface (SPI) that can be configured as master or slave. The SPI Interface pins are mapped, as shown in the following table. The SPI Interface is a full-duplex slave-synchronous serial interface. When the SPI is not selected, i.e., when SSN is high, the SPI interface will not interfere with data transfers between the serial master and other serial slave devices. When the serial slave is not selected, its transmitted data output is buffered, resulting in a high impedance drive onto the serial master receive line. The SPI slave interface responds to a protocol that allows an external host to read or write any register in the chip as well as initiate DMA transfers.

Table 10-4. SPI Interface Pin Mapping

Pin Name	SPI Function
SSN	Active Low Slave Select
SCK	Serial Clock
MOSI	Master Out Slave In (Data)
MISO	Master In Slave Out (Data)

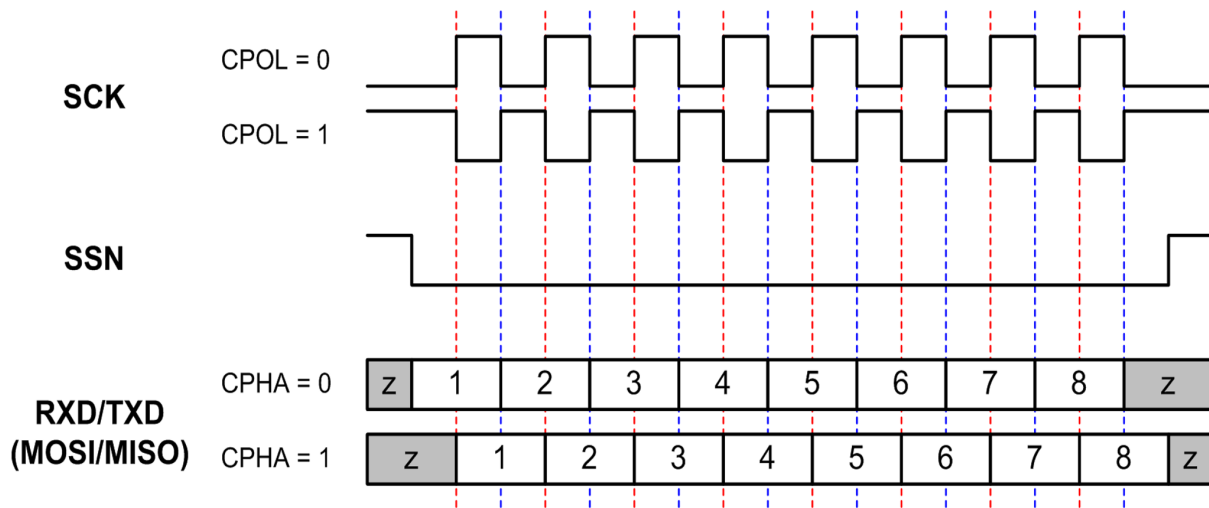
10.3.2 SPI Interface Modes

The SPI Interface supports four standard modes as determined by the Clock Polarity (CPOL) and Clock Phase (CPHA) settings. These modes are illustrated in [Table SPI Modes](#) and [Figure SPI Clock Polarity and Clock Phase Timing](#). The red lines in [Figure SPI Clock Polarity and Clock Phase Timing](#) correspond to Clock Phase = 0 and the blue lines correspond to Clock Phase = 1.

Table 10-5. SPI Modes

Mode	CPOL	CPHA
0	0	0
1	0	1
2	1	0
3	1	1

Figure 10-1. SPI Clock Polarity and Clock Phase Timing



10.4 UART Interface

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA provide Universal Asynchronous Receiver/Transmitter (UART) interfaces for serial communication. The Bluetooth subsystem contains two UART interfaces: 2-Pin interface with TX and RX, and a 4-pin interface with TX and RX and hardware flow control (RTS and CTS). The UART interfaces are compatible with the RS-232 standard, where the ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA operate as Data Terminal Equipment (DTE).



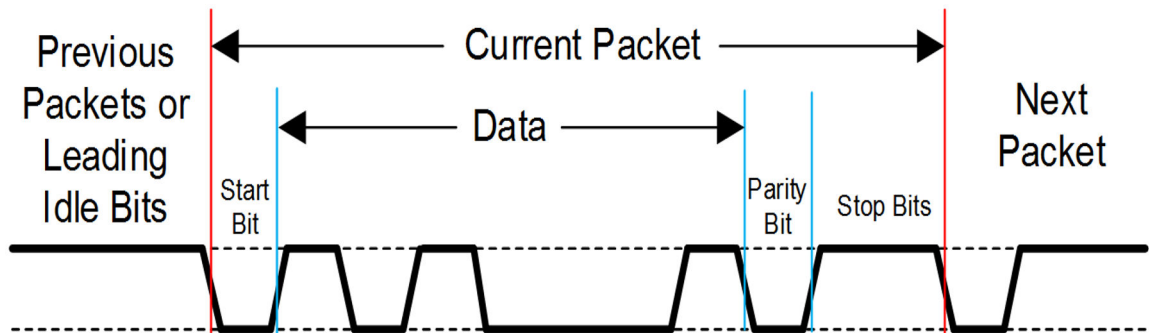
The RTS and CTS are used for hardware flow control. The RTS and CTS pins must be connected to the host MCU UART and enabled for the UART interface to be functional..

The pins associated with each UART interface can be enabled on several alternative pins by programming their corresponding pin-MUX control registers (see [Table Pin-MUX Matrix of External Interfaces](#) and [Table Software Selectable MEGAMUX Options](#) for available options).

The UART features the programmable baud rate generation with fractional clock division, which allows transmission and reception at a wide variety of standard and non-standard baud rates. The Bluetooth UART input clock is selectable between 26 MHz, 13 MHz, 6.5 MHz, and 3.25 MHz. The clock divider value is programmable as 13 integer bits and three fractional bits (with 8.0 being the smallest recommended value for normal operation). This results in the maximum supported baud rate of $26 \text{ MHz} / 8.0 = 3.25 \text{ MBd}$.

The UART can be configured for 7-bit or 8-bit operation, with or without parity, with four different parity types (odd, even, mark, or space), and with one or two stop bits. It also contains RX and TX FIFOs, which ensure reliable high-speed reception and low software overhead transmission. FIFO size is 4 x 8 for both RX and TX direction. The UART also contains status registers showing the number of received characters available in the FIFO and various error conditions, and also the ability to generate interrupts based on these status bits.

An example of UART receiving or transmitting a single packet is shown in [Figure Example of UART RX or TX Packet](#). This example shows 7-bit data (0x45), odd parity, and two stop bits.

Figure 10-2. Example of UART RX or TX Packet


10.5 GPIOs

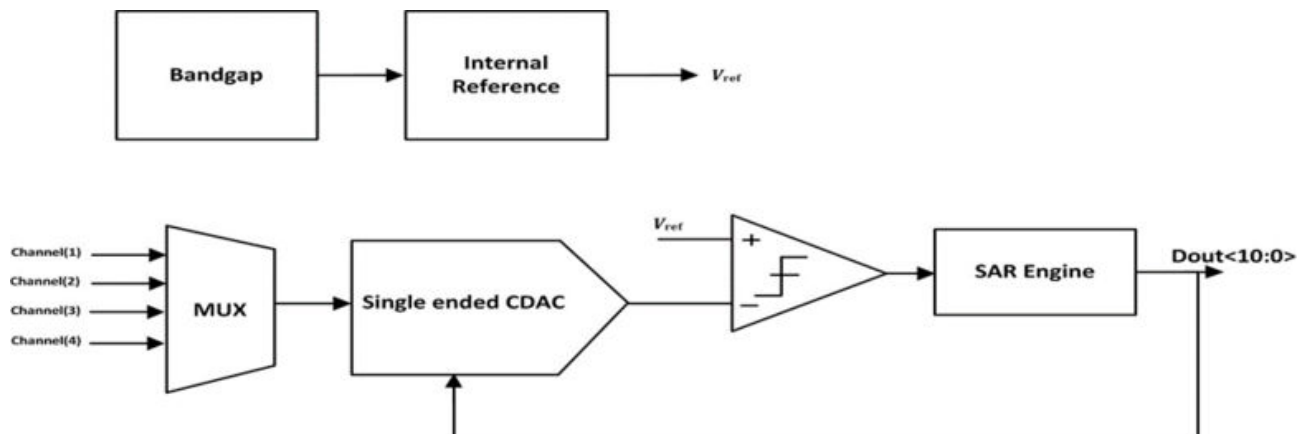
The 29 General Purpose Input/Output (GPIO) pins, labeled LP_GPIO (22), GPIO_MS (4), and AO_GPIO (3), are available to allow for application-specific functions. Each GPIO pin can be programmed as an input (the value of the pin can be read by the host or internal processor) or as an output. The host or internal processor can program the output values.

The LP_GPIO pins are digital interface pins, GPIO_MS pins are mixed signal/analog interface pins, and AO_GPIO pins are always-on digital interface pins. AO_GPIO_0 can detect interrupt signals in deep sleep mode for wake-up purposes.

The LP_GPIO have interrupt capability, only during inactive/standby mode. In Sleep mode, they are turned off to save power consumption.

10.6 Analog to Digital Converter

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have an integrated Successive Approximation Register (SAR) ADC with 11-bit resolution and variable conversion speed up to 1MS/s. The key building blocks are the capacitive DAC, comparator, and synchronous SAR engine as illustrated in the following figure.

Figure 10-3. SAR ADC Block Diagram


The ADC reference voltage can be either generated internally or set externally via one of the four available Mixed Signal GPIO pins on the ATBTLC1000-XR1100A and the ATBTLC1000-ZR110CA.

There are two modes of operation:

- High resolution (11-bit): Set the reference voltage to half the supply voltage or below. In this condition the input signal dynamic range is equal to twice the reference voltage (ENOB=10-bit).
- Medium Resolution (10-bit) : Set the reference voltage to any value below supply voltage (up to supply voltage - 300 mV) and in this condition the input dynamic range is from zero to the reference voltage (ENOB = 9-bit).

Four input channels are time multiplexed to the input of the SAR ADC. However, on the ATBTLC1000, only four channel inputs are accessible from the outside, through the pins 28, 29, 31, and 32 (Mixed Signal GPIO pins) listed in [Table 10-1](#).

In Power-Saving mode, the internal reference voltage is completely off and the reference voltage is set externally.

The ADC characteristics are summarized in the following table.

Table 10-6. SAR ADC Characteristics

Conversion rate	1 ks → 1 MS
Selectable Resolution	10 → 11 bit
Power consumption	13.5 μ A (at 100 KS/s) ¹

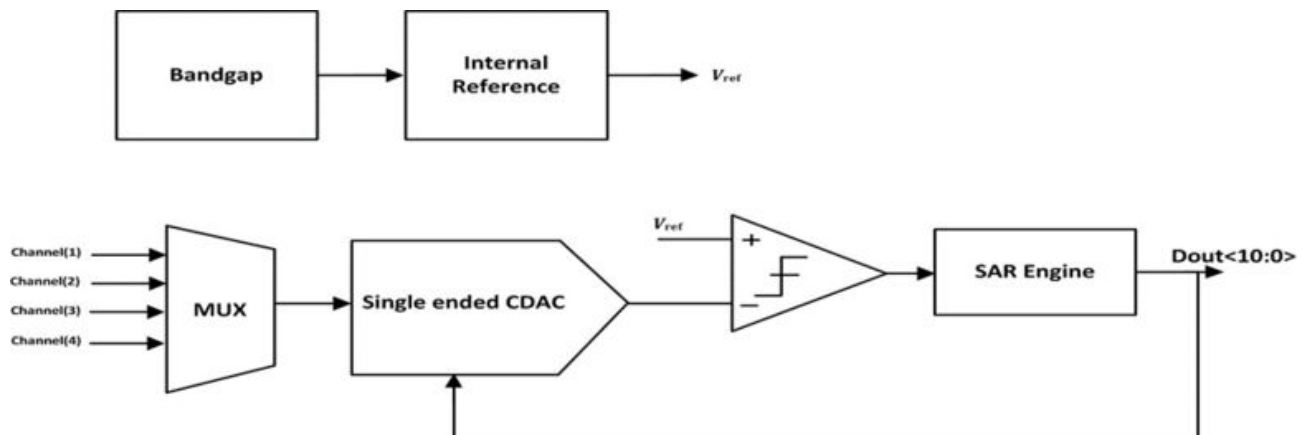
Note:

1. With external reference.

10.6.1 Overview

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have an integrated Successive Approximation Register (SAR) ADC with 11-bit resolution and variable conversion speed is 1 MS/s. The key building blocks are the capacitive DAC, comparator, and synchronous SAR engine, as illustrated in [Figure SAR ADC Block Diagram](#).

Figure 10-4. SAR ADC Block Diagram



The ADC reference voltage can be either generated internally or set externally through one of the four available Mixed Signal GPIO pins on the ATBTLC1000-XR1100A and the ATBTLC1000-ZR110CA.

There are two modes of operation:

- High resolution (11-bit): Set the reference voltage to half the supply voltage or below. In this condition, the input signal dynamic range is equal to twice the reference voltage (ENOB=10-bit).

- Medium Resolution (10-bit) : Set the reference voltage to any value below the supply voltage (up to supply voltage = 300 mV) and in this condition the input dynamic range is from zero to the reference voltage (ENOB = 9-bit).

Four input channels are time multiplexed to the input of the SAR ADC. However, on the ATBTLC1000, only four channel inputs are accessible from the outside, through the pins 28, 29, 31, and 32 (Mixed Signal GPIO pins).

In power saving mode, the internal reference voltage is completely off and the reference voltage is set externally.

The ADC characteristics are summarized in [Table SAR ADC Characteristics](#).

Table 10-7. SAR ADC Characteristics

Conversion rate	1 ks → 1 MS
Selectable Resolution	10 → 11 bit
Power consumption	13.5 µA (at 100 KS/s) ⁽¹⁾

Note:

1. With external reference.

10.6.2 Timing

The ADC timing is shown in [Figure SAR ADC Timing](#). The input signal is sampled twice. In the first sampling cycle, the input range is defined either to be above reference voltage or below it, and in the second sampling instant the ADC starts its normal operation.

The ADC takes two sampling instants and N-1 conversion cycle (N=ADC resolution), and one cycle to sample the data out. Therefore, for the 11-bit resolution, it takes 13 clock cycles to do one sample conversion.

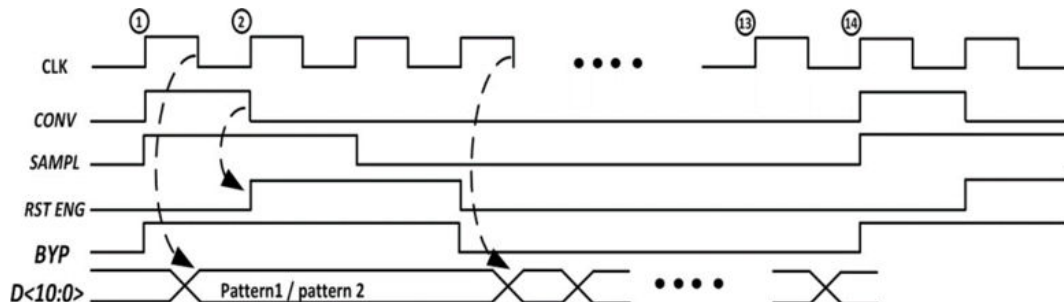
The input clock equals N+2, the sampling clock frequency (N is the ADC resolution).

CONV signal : Gives indication about the end of conversion.

SAMPL : The input signal is sampled, when this signal is high.

RST ENG : When high SAR engine is in Reset mode (SAR engine output is set to mid-scale).

Figure 10-5. SAR ADC Timing



10.7 Software Programmable Timer and Pulse Width Modulator

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA contain four individually configurable pulse width modulator (PWM) blocks to provide external control voltages. The base frequency of the PWM

block (f_{PWM_base}) is derived from the XO clock (26 MHz) or the RC oscillator followed by a programmable divider.

The frequency of each PWM pulse (f_{PWM}) is programmable in steps according to the following relationship:

$$f_{PWM} = \frac{f_{PWM_base}}{64 \cdot 2^i} \quad i = 0, 1, 2, \dots, 8$$

The duty cycle of each PWM signal is configurable with 10-bit resolution (minimum duty cycle is 1/1024 and the maximum is 1023/1024).

f_{PWM_base} can be selected to have different values according to [Table \$f_{PWM}\$ Range for Different \$f_{PWM}\$ Base Frequencies](#). The minimum and maximum frequencies supported for each clock selection are also listed in the table.

Table 10-8. f_{PWM} Range for Different f_{PWM} Base Frequencies

f_{PWM_base}	f_{PWM} max.	f_{PWM} min.
26 MHz	406.25 kHz	1.586 kHz
13 MHz	203.125 kHz	793.25 Hz
6.5 MHz	101.562 kHz	396.72 Hz
3.25 MHz	50.781 kHz	198.36 Hz

10.8 Clock Output

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have an option to output a clock. The clock can be output to any GPIO pin through the test MUX. Note that this feature requires that the ARM and BLE power domains stay on. If BLE is not used, the clocks to the BLE core are gated off, resulting in small leakage. The following two methods can be used to output a clock.

Note: Refer to the BluSDK BLE API Software Development Guide for details on how to enable the 32.768 kHz clock output.

10.8.1 Variable Frequency Clock Output Using Fractional Divider

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA can output the variable frequency ADC clock using a fractional divider of the 26 MHz oscillator. This clock needs to be enabled using bit 10 of the `lpmcu_clock_enables_1` register. The clock frequency can be controlled by the divider ratio using the `sens_adc_clk_ctrl` register (12-bits integer part, 8-bit fractional part). The division ratio can vary from 2 to 4096 delivering output frequency between 6.35 kHz to 13 MHz. This is a digital divider with pulse swallowing implementation, so the clock edges may not be at exact intervals for the fractional ratios; however, it is exact for integer division ratios.

10.8.2 Fixed Frequency Clock Output

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA can output the following fixed-frequency clocks:

- 52 MHz derived from XO
- 26 MHz derived from XO
- 2 MHz derived from the 2 MHz RC Osc.
- 31.25 kHz derived from the 2 MHz RC Osc.
- 32.768 kHz derived from the RTC XO

- 26 MHz derived from 26 MHz RC Osc.
- 6.5 MHz derived from XO
- 3.25 MHz derived from 26 MHz RC Osc.

For clocks with frequency of 26 MHz and above, ensure that the external pad load on the board is minimized to get a clean waveform.

10.9 Three-axis Quadrature Decoder

The ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA have a three-axis Quadrature decoder (X, Y, and Z) that can determine the direction and speed of movement on three axes, requiring in total six GPIO pins to interface with the sensors. The sensors are expected to provide pulse trains as inputs to the quadrature decoder.

Each axis channel input will have two pulses with ± 90 degrees phase shift depending on the direction of movement. The decoder counts the edges of the two waveforms to determine the speed and uses the phase relationship between the two inputs to determine the direction of motion.

The decoder is configured to interrupt ARM based on independent thresholds for each direction. Each quadrature clock counter (X, Y, and Z) is an unsigned 16-bit counter and the system clock uses a programmable sampling clock ranging from 26 MHz, 13, 6.5, to 3.25 MHz.

If wake-up is desired from threshold detection on an axis input, an always-on GPIO needs to be used (there are three always-on GPIOs on ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA).

11. Electrical Characteristics

There are voltage ranges, where different VDDIO levels apply. The reason for this separation is for the IO drivers, whose drive strength is directly proportional to the IO supply voltage. In the ATBTLC1000 products, there is a large gap in the IO supply voltage range (1.8V to 4.3V). A guarantee on drive strength across this voltage range will be intolerable to most vendors, who only use a subsection of the IO supply range. As such, these voltages are segmented into three manageable sections referenced as VDDIOL, VDDIOM, and VDDIOH in tables listed in this document.

11.1 Absolute Maximum Ratings

Table 11-1. Absolute Maximum Ratings

Symbol	Characteristics	Min.	Max.	Unit
VDDIO	I/O Supply Voltage	-0.3	5.0	V
VBAT	Battery Supply Voltage	-0.3	5.0	
V _{IN} ⁽¹⁾	Digital Input Voltage	-0.3	VDDIO	
V _{AIN} ⁽²⁾	Analog Input Voltage	-0.3	1.5	
T _A	Storage Temperature	-65	150	°C

Note:

1. V_{IN} corresponds to all the digital pins.
2. V_{AIN} corresponds to all the analog pins, RFIO, XO_N, XO_P, TPP, RTC_CLK_N and RTC_CLK_P.

11.2 Recommended Operating Conditions

Table 11-2. Recommended Operating Conditions

Symbol	Characteristic	Min.	Typ.	Max.	Unit
VDDIO _L	I/O Supply Voltage Low Range	1.62	1.80	2.00	V
VDDIO _M	I/O Supply Voltage Mid-Range	2.0	2.50	3.00	
VDDIO _H	I/O Supply Voltage High Range	3.00	3.30	3.60	
VBAT	Battery Supply Voltage ⁽¹⁾	1.8	3.6	4.3	
	Operating Temperature	-40		85	°C

Note:

1. VBAT must not be less than VDDIO.
2. When powering-up the device, VBAT must be greater or equal to 1.9V to ensure BOD does not trigger. BOD threshold is typically 1.8V and the device will be held in reset, if VBAT is near this threshold on startup. After startup, BOD can be disabled and the device can operate down to 1.8V.

11.3 DC Characteristics

The [DC Electrical Characteristics Table](#) provides the DC characteristics for the digital pads.

Table 11-3. DC Electrical Characteristics

VDDIO Condition	Characteristic	Min.	Typ.	Max.	Unit
VDDIO _L	Input Low Voltage V _{IL}	-0.30		0.60	V
	Input High Voltage V _{IH}	VDDIO-0.60		VDDIO+0.30	
	Output Low Voltage V _{OL}			0.45	
	Output High Voltage V _{OH}	VDDIO-0.50			
VDDIO _M	Input Low Voltage V _{IL}	-0.30		0.63	
	Input High Voltage V _{IH}	VDDIO-0.60		VDDIO+0.30	
	Output Low Voltage V _{OL}			0.45	
	Output High Voltage V _{OH}	VDDIO-0.50			
VDDIO _H	Input Low Voltage V _{IL}	-0.30		0.65	
	Input High Voltage V _{IH}	VDDIO-0.60		VDDIO+0.30 (up to 3.60)	
	Output Low Voltage V _{OL}			0.45	
	Output High Voltage V _{OH}	VDDIO-0.50			
All	Output Loading			20	pF
	Digital Input Load			6	
VDDIO _L	Pad drive strength (regular pads ⁽¹⁾)	1.7	2.5		mA
VDDIO _M	Pad drive strength (regular pads ⁽¹⁾)	3.4	6.6		
VDDIO _H	Pad drive strength (regular pads ⁽¹⁾)	10.5	14		
VDDIO _L	Pad drive strength (regular pads ⁽¹⁾)	3.4	5.0		
VDDIO _M	Pad drive strength (high-drive pads ⁽¹⁾)	6.8	13.2		
VDDIO _H	Pad drive strength (high-drive pads ⁽¹⁾)	21	28		

Note:

- The following GPIO pads are high-drive pads: GPIO_8 and GPIO_9; all other pads are regular pads.

11.4 Current Consumption in Various Device States

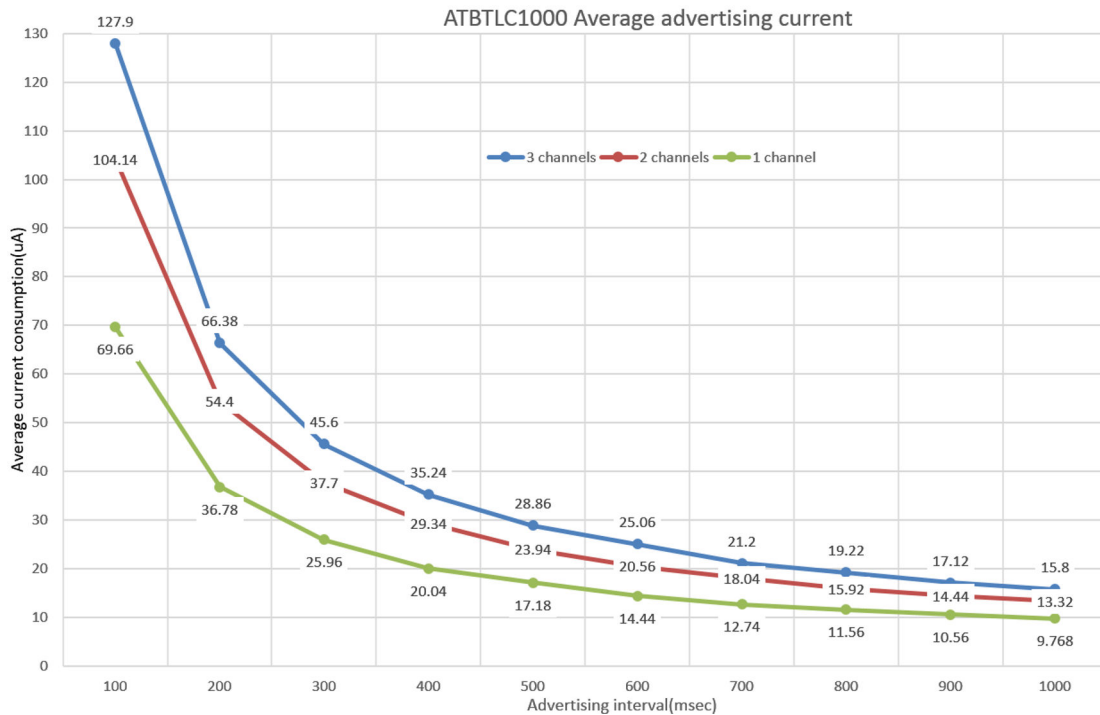
Table 11-4. Device State Current Consumption

Device State	C_EN	VDDIO	I _{VBAT} +I _{VDDIO} (typical) ⁽²⁾
Power_Down	Off	On	0.04 μ A
Ultra_Low_Power with BLE timer, with RTC ⁽¹⁾	On	On	1.88 μ A
BLE_On_Receive @Channel 37 (2402 MHz)	On	On	5.66 mA
BLE_On_Transmit, 0 dBm output power @Channel 37 (2402 MHz)	On	On	4.78 mA
BLE_On_Transmit, 0 dBm output power @Channel 39 (2480 MHz)	On	On	4.33 mA
BLE_On_Transmit, 3 dBm output power @Channel 37 (2480 MHz)	On	On	6.20 mA
BLE_On_Transmit, 3 dBm output power @Channel 39 (2480 MHz)	On	On	5.43 mA

Note:

1. Sleep clock derived from external 32.768 kHz crystal specified for CL = 7 pF, using the default on-chip capacitance only, without using external capacitance.
2. Measurement conditions:
 - 2.1. VBAT=3.3V
 - 2.2. VDDIO=3.3V
 - 2.3. Temperature=25°C
 - 2.4. These measurements are taken with FW BluSDK V6.1.7072

Figure 11-1. Average Advertising Current



Note:

1. The average advertising current is measured at VBAT = 3.3 V, VDDIO = 3.3 V, TX output power = 0 dBm and temperature - 25°C.
2. Advertisement data payload size - 31 octets.
3. Advertising event type - connectable undirected.
4. Advertising channels used in 2 channel : 37 and 38.
5. Advertising channels used in 1 channel: 37.

11.5 Receiver Performance

Table 11-5. BLE Receiver Performance

Parameter	Minimum	Typical	Maximum	Unit
Frequency	2,402		2,480	MHz
Sensitivity with on-chip DC/DC ⁽¹⁾	-91.5	-90		dBm
Maximum receive signal level		+5		
CCI		12.5		dB
ACI (N±1)		0		
N+2 Blocker (Image)		-20		
N-2 Blocker		-38		
N+3 Blocker (Adj. Image)		-35		
N-3 Blocker		-43		

.....continued				
Parameter	Minimum	Typical	Maximum	Unit
N±4 or greater		-45		dBm
Intermod (N+3, N+6)		-32		
OOB (2 GHz<f<2.399 GHz)	-15			
OOB (f<2 GHz or f>2.5 GHz)	-10			

All measurements are taken after the RF input matching network. Refer to the [13. ATBTLC1000 Schematics](#).

All measurements are performed at 3.3V VBAT and 25°C, with tests following the Bluetooth standard tests.

Note:

1. Typical receiver sensitivity is average across 40 channels.

11.6 Transmitter Performance

The transmitter contains fine step power control with P_{out} variable in <3 dB steps below 0 dBm and in <0.5 dB steps above 0 dBm.

Table 11-6. BLE Transmitter Performance

Parameter	Minimum	Typical	Maximum	Unit
Frequency	2,402		2,480	MHz
Maximum Output Power		3.5 ⁽¹⁾		dBm
In-band Spurious (N±2)		-45		
In-band Spurious (N±3)		-50		
2nd harmonic P _{out}	-41			
3rd harmonic P _{out}	-41			
4th harmonic P _{out}	-41			
5th harmonic P _{out}	-41			
Frequency deviation		±250		kHz

All measurements are taken after the RF input matching network. Refer to the [13. ATBTLC1000 Schematics](#).

All measurements are performed at 3.3V VBAT and 25°C, with tests following the Bluetooth standard tests.

Note:

1. Country specific transmit power settings (as per the ATBTLC1000-ZR110CA Certifications) should be programmed at the Host product factory to match the intended destination. Regulatory bodies prohibit exposing the transmit power settings, that would configure the transmit power beyond certified limits, to the end user. This requirement needs to be taken care of via Host implementation.

11.7 ADC Characteristics
Table 11-7. Static Performance of SAR ADC

Parameter	Condition	Min.	Typ.	Max.	Unit
Input voltage range		0		VBAT	V
Resolution			11		bits
Sample rate			100	1000	KSPS
Input offset	Internal VREF	-10		+10	mV
Gain error	Internal VREF	-4		+4	%
DNL	100 KSPS. Internal VREF=1.6V. Same result for external VREF.	-0.75		+1.75	LSB
INL	100 KSPS. Internal VREF=1.6V. Same result for external VREF.	-2		+2.5	LSB
THD	1 kHz sine input at 100 KSPS		73		dB
SINAD	1 kHz sine input at 100 KSPS		62.5		dB
SFDR	1 kHz sine input at 100 KSPS		73.7		dB
Conversion time			13		cycles
Current consumption	Using external VREF, at 100 KSPS		13.5		μA
	Using internal VREF, at 100 KSPS		25.0		μA
	Using external VREF, at 1 MSPS		94		μA
	Using internal VREF, at 1 MSPS		150		μA
	Using internal VREF, during VBAT monitoring		100		μA
	Using internal VREF, during temperature monitoring		50		μA
Internal reference voltage	Mean value using VBAT = 2.5V		1.026 ⁽¹⁾		V
	Standard deviation across parts		10.5		mV
VBAT Sensor Accuracy	Without calibration	-55		+55	mV
	With offset and gain calibration	-17		+17	mV
Temperature Sensor Accuracy	Without calibration	-9		+9	°C
	With offset calibration	-4		+4	°C

Note:

1. Effective VREF is 2xInternal Reference Voltage.

11.8 ADC Typical Characteristics

$T_C = 25^\circ\text{C}$ and $V_{BAT} = 3.0\text{V}$, unless otherwise noted.

Figure 11-2. INL of SAR ADC

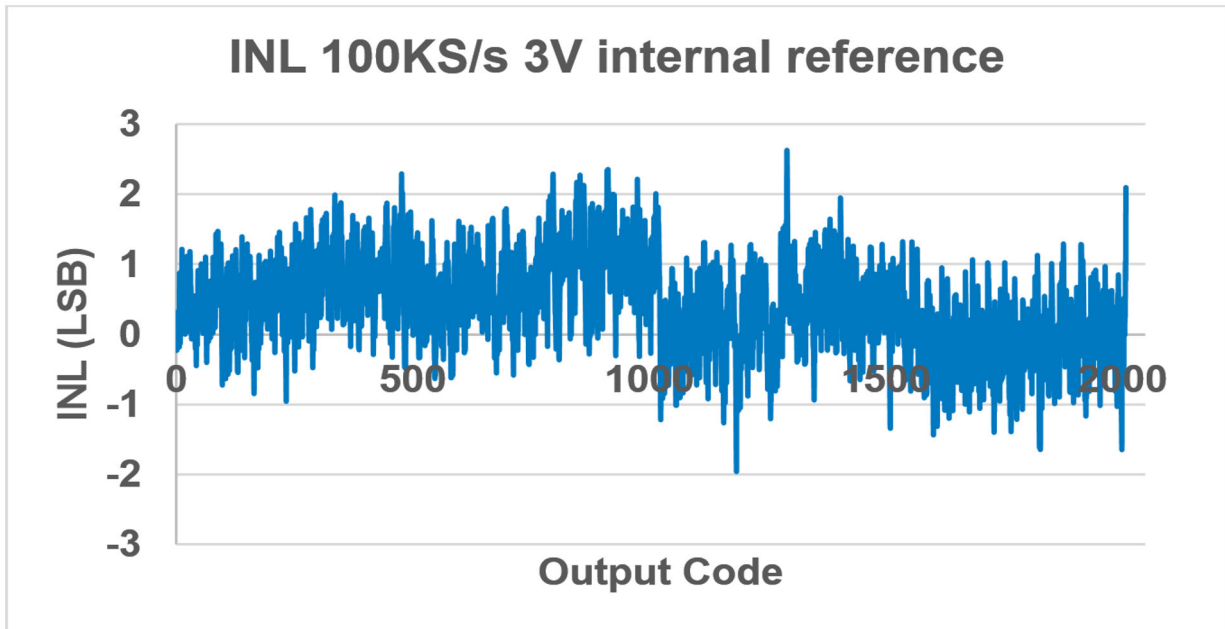


Figure 11-3. DNL of SAR ADC

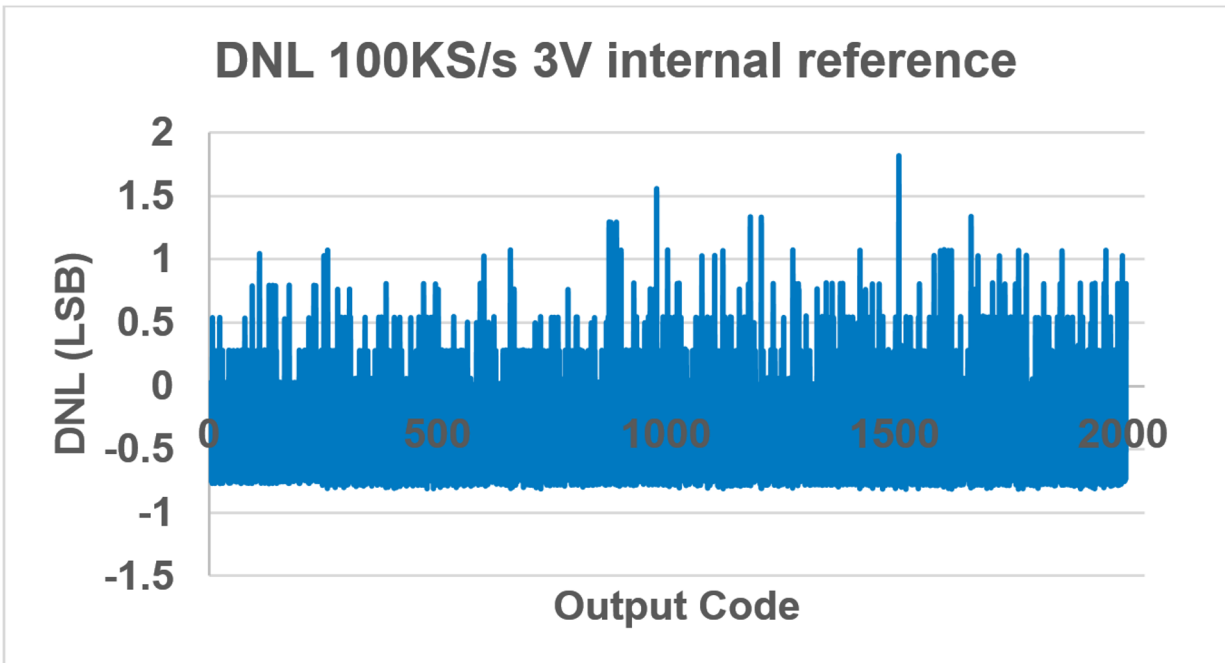
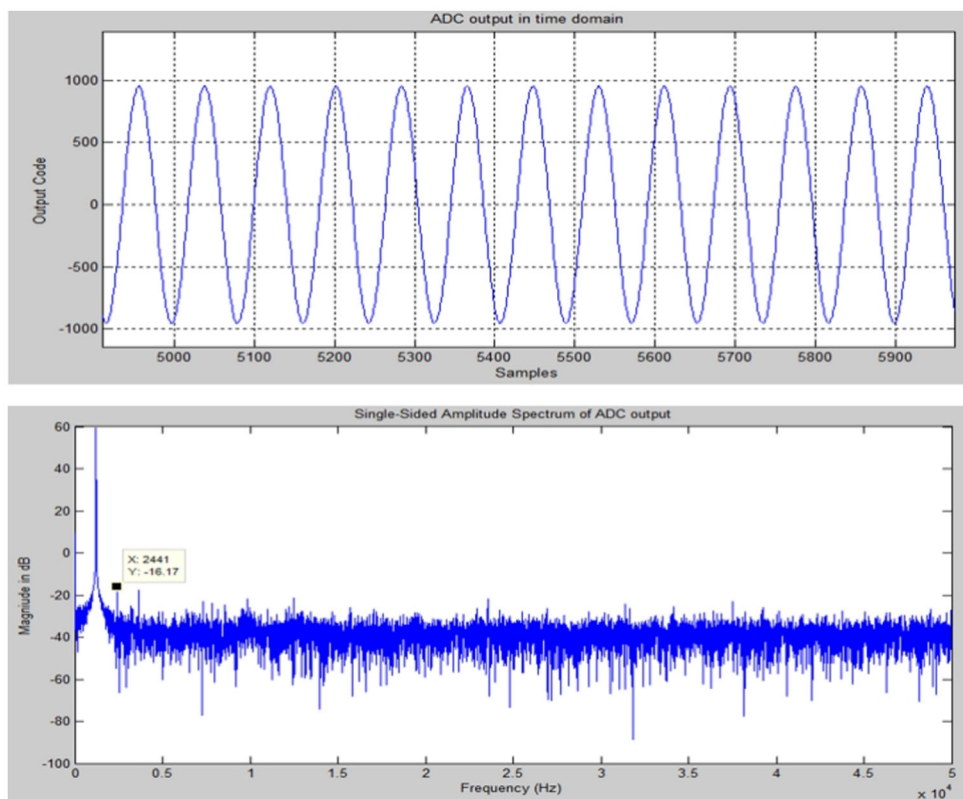
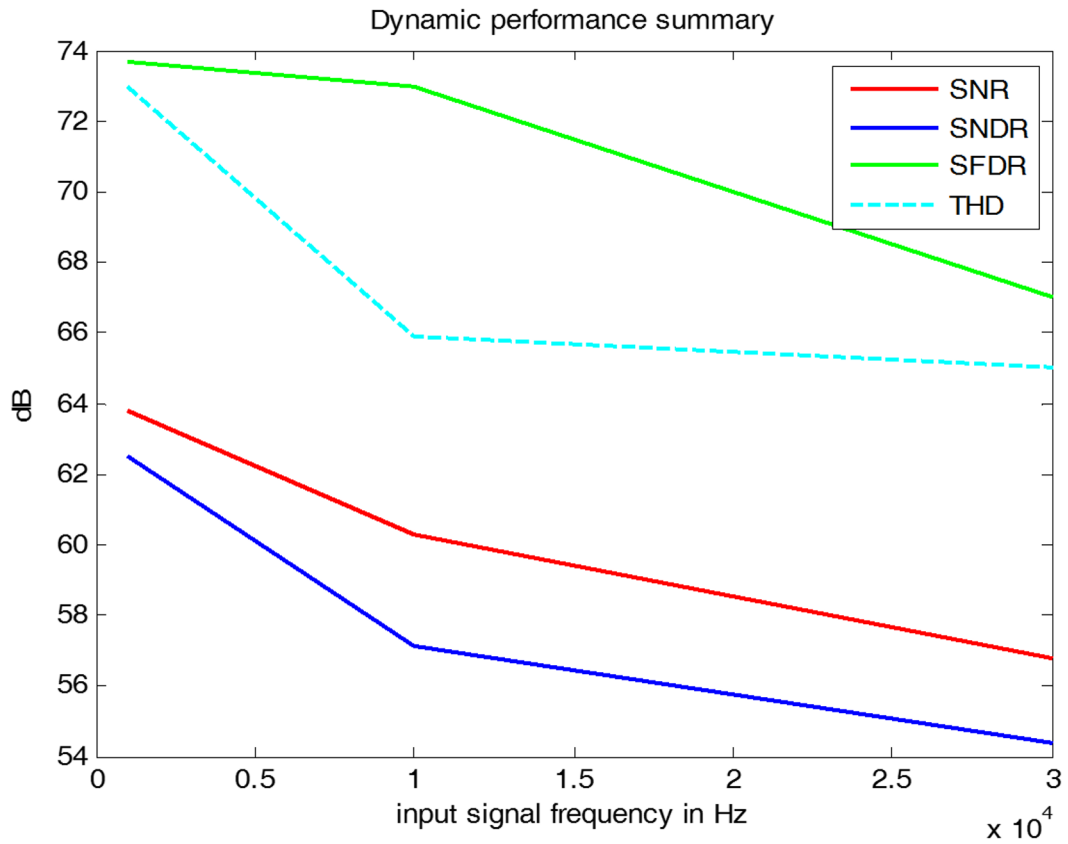


Figure 11-4. Sensor ADC Dynamic Measurement with Sinusoidal Input

Note:

1. 25°C, 3.6V VBAT, and 100 kS/s
Input signal: 1 kHz sine wave, 3Vp-p amplitude.
2. SNDR = 62.5 dB
, SFDR = 73.7 dB and
THD = 73.0 dB.

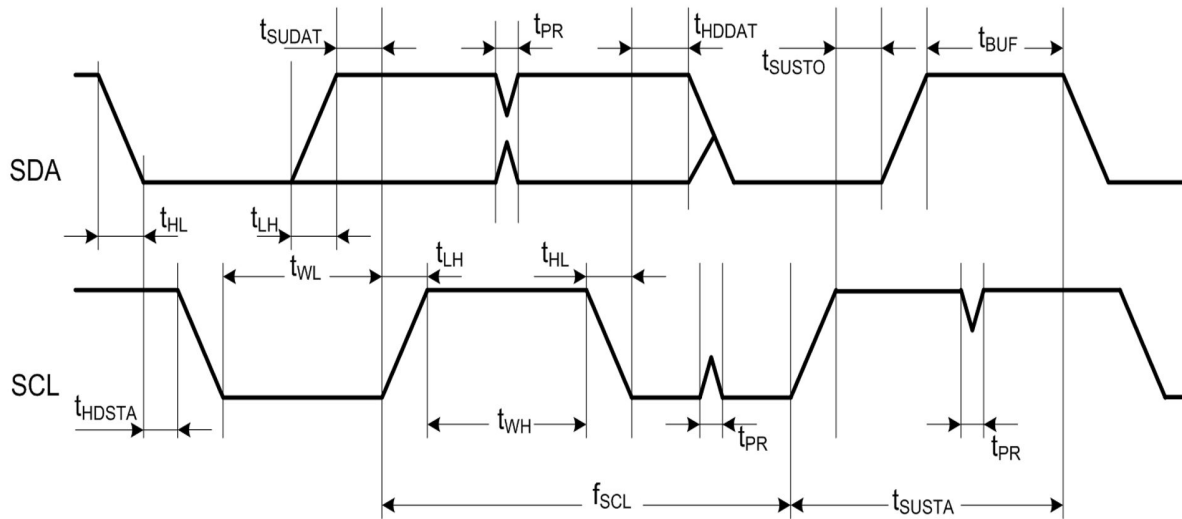
Figure 11-5. Sensor ADC Dynamic Performance Summary at 100 KSPS



11.9 Timing Characteristics

11.9.1 I²C Interface Timing

The I²C Interface timing (common to both Slave and Master) is provided in [I2C Slave Timing Diagram](#). The timing parameters for Slave and Master modes are specified in tables [I2C Slave Timing Parameters](#) and [I2C Master Timing Parameters](#) respectively.

Figure 11-6. I²C Slave Timing Diagram

Table 11-8. I²C Slave Timing Parameters

Parameter	Symbol	Min.	Max.	Units	Remarks
SCL Clock Frequency	f_{SCL}	0	400	kHz	
SCL Low Pulse Width	t_{WL}	1.3		μs	
SCL High Pulse Width	t_{WH}	0.6		μs	
SCL, SDA Fall Time	t_{HL}		300	ns	This is dictated by external components
SCL, SDA Rise Time	t_{LH}		300	ns	
START Setup Time	t_{SUSTA}	0.6		μs	
START Hold Time	t_{HDSTA}	0.6		μs	
SDA Setup Time	t_{SUDAT}	100		ns	Slave and Master Default Master Programming Option
SDA Hold Time	t_{HDDAT}	0 40		ns	
STOP Setup time	t_{SUSTO}	0.6		μs	
Bus Free Time between STOP and START	t_{BUF}	1.3		μs	
Glitch Pulse Reject	t_{PR}	0	50	ns	

Table 11-9. I²C Master Timing Parameters

Parameter	Symbol	Standard Mode		Fast Mode		High-speed Mode		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
SCL Clock Frequency	f_{SCL}	0	100	0	400	0	3400	kHz

.....continued								
Parameter	Symbol	Standard Mode		Fast Mode		High-speed Mode		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
SCL Low Pulse Width	t_{WL}	4.7		1.3		0.16		μs
SCL High Pulse Width	t_{WH}	4		0.6		0.06		
SCL Fall Time	t_{HLSCL}		300		300	10	40	ns
SDA Fall Time	t_{HLSDA}		300		300	10	80	
SCL Rise Time	t_{LHSCL}		1000		300	10	40	
SDA Rise Time	t_{LHSDA}		1000		300	10	80	
START Setup Time	t_{SUSTA}	4.7		0.6		0.16		μs
START Hold Time	t_{HDSTA}	4		0.6		0.16		
SDA Setup Time	t_{SUDAT}	250		100		10		ns
SDA Hold Time	t_{HDDAT}	5		40		0	70	
STOP Setup time	t_{SUSTO}	4		0.6		0.16		μs
Bus Free Time between STOP and START	t_{BUF}	4.7		1.3				
Glitch Pulse Reject	t_{PR}			0	50			ns

11.9.2 SPI Slave Timing

The SPI Slave timing is provided in the following figure and tables.

Figure 11-7. SPI Slave Timing Diagram

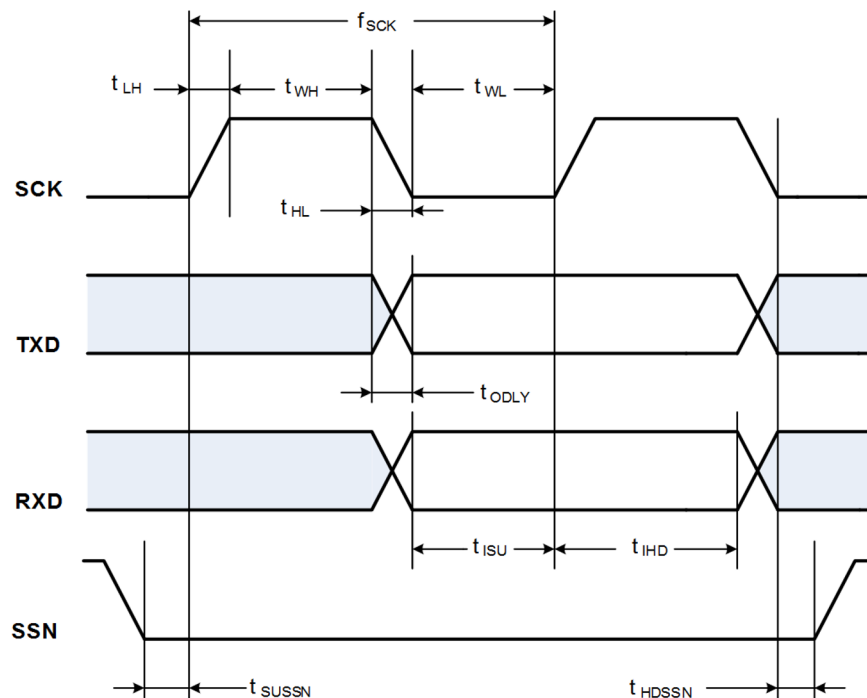


Table 11-10. SPI Slave Timing Parameters ⁽¹⁾

Parameter	Symbol	Min.	Max.	Units
Clock Input Frequency ⁽²⁾	f_{SCK}		2	MHz
Clock Low Pulse Width	t_{WL}	55		ns
Clock High Pulse Width	t_{WH}	55		
Clock Rise Time	t_{LH}	0	7	
Clock Fall Time	t_{HL}	0	7	
TXD Output Delay ⁽³⁾	t_{ODLY}	7	28	
RXD Input Setup Time	t_{ISU}	5		
RXD Input Hold Time	t_{IHD}	10		
SSN Input Setup Time	t_{SUSSN}	5		
SSN Input Hold Time	t_{HDSSN}	10		

Note:

1. Timing is applicable to all SPI modes.
2. Maximum clock frequency specified is limited by the SPI Slave interface internal design. Actual maximum clock frequency can be lower and depends on the specific PCB layout.
3. Timing is based on 15 pF output loading.

11.9.3 SPI Master Timing

The SPI Master Timing is provided in the following figure and table.

Figure 11-8. SPI Master Timing Diagram

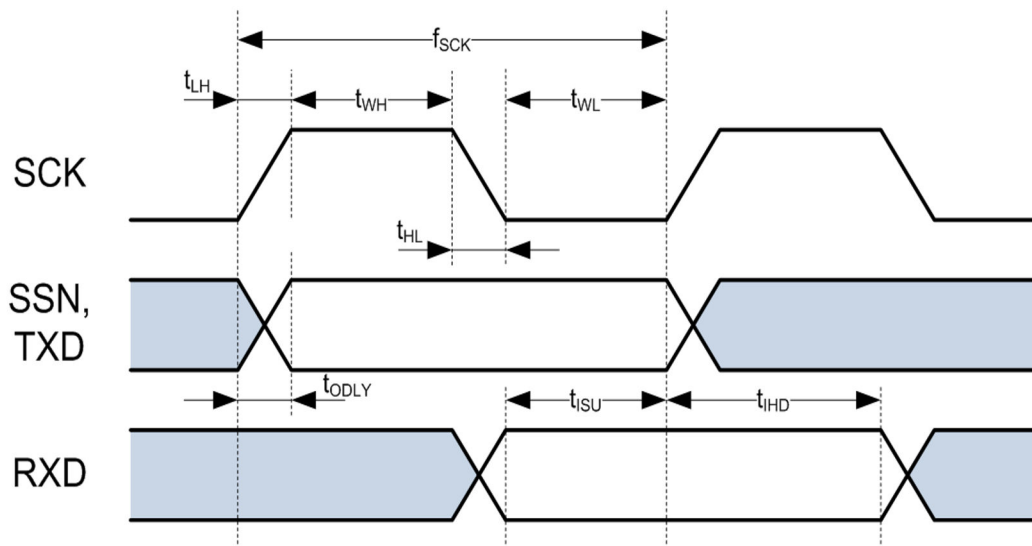


Table 11-11. SPI Master Timing Parameters ⁽¹⁾

Parameter	Symbol	Min.	Max.	Units
Clock Output Frequency ⁽²⁾	f_{SCK}		4	MHz
Clock Low Pulse Width	t_{WL}	30		ns
Clock High Pulse Width	t_{WH}	32		
Clock Rise Time ⁽²⁾	t_{LH}		7	
Clock Fall Time ⁽²⁾	t_{HL}		7	
RXD Input Setup Time	t_{ISU}	23		
RXD Input Hold Time	t_{IHD}	0		
SSN/TXD Output Delay ⁽³⁾	t_{ODLY}	0	12	

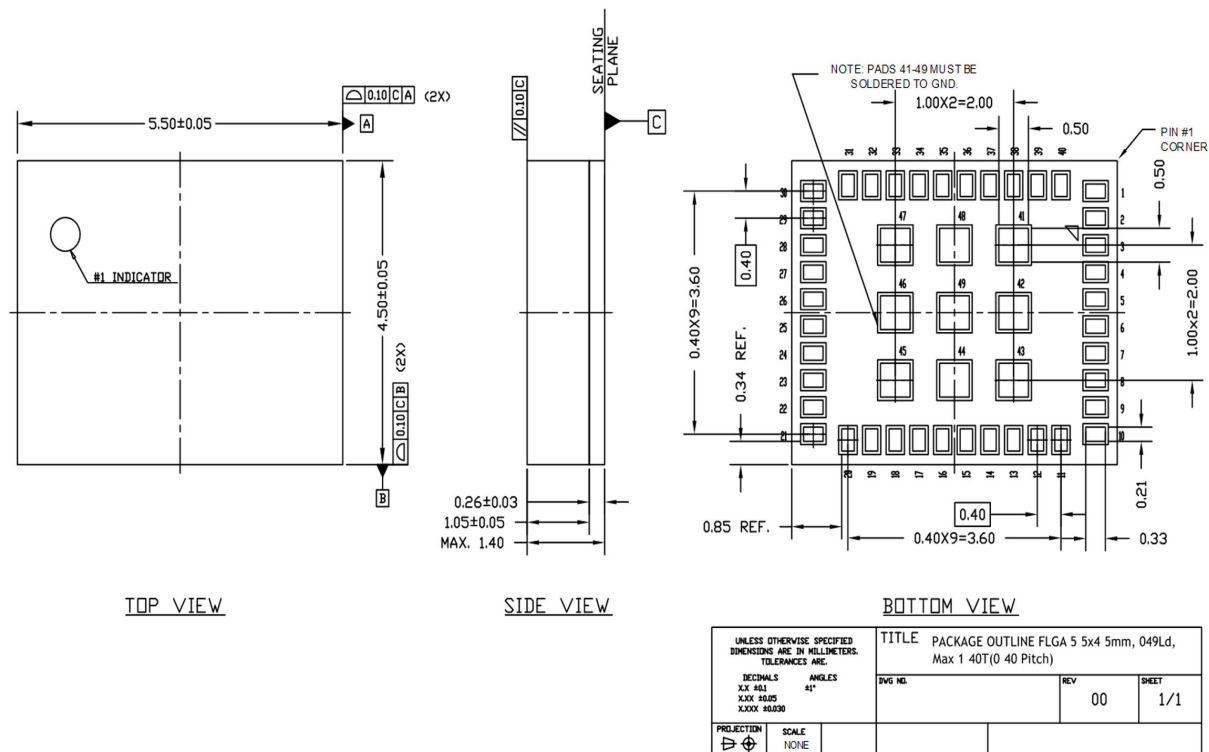
Note:

1. Timing is applicable to all SPI modes.
2. Maximum clock frequency specified is limited by the SPI Master interface internal design. The actual maximum clock frequency can be lower and depends on the specific PCB layout.
3. Timing is based on 15 pF output loading.

12. Package Outline Drawings

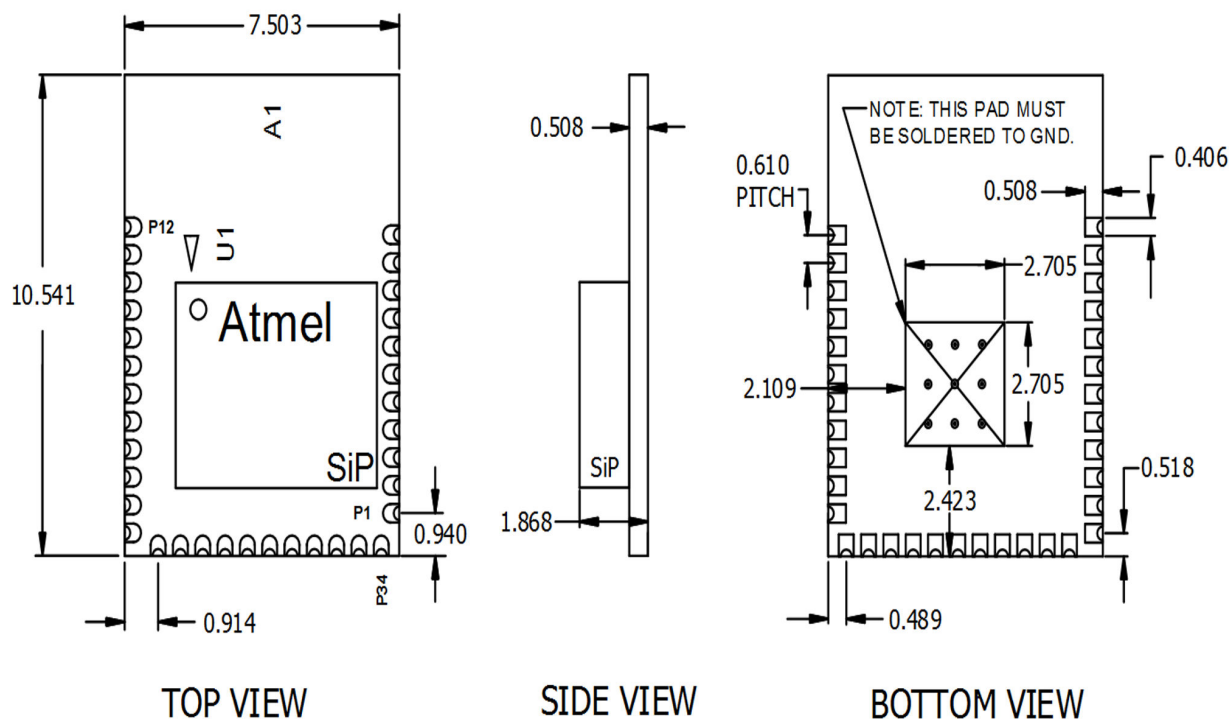
12.1 ATBTLC1000-XR1100A Package Outline Drawing

Figure 12-1. ATBTLC1000-XR1100A Package Outline Drawing



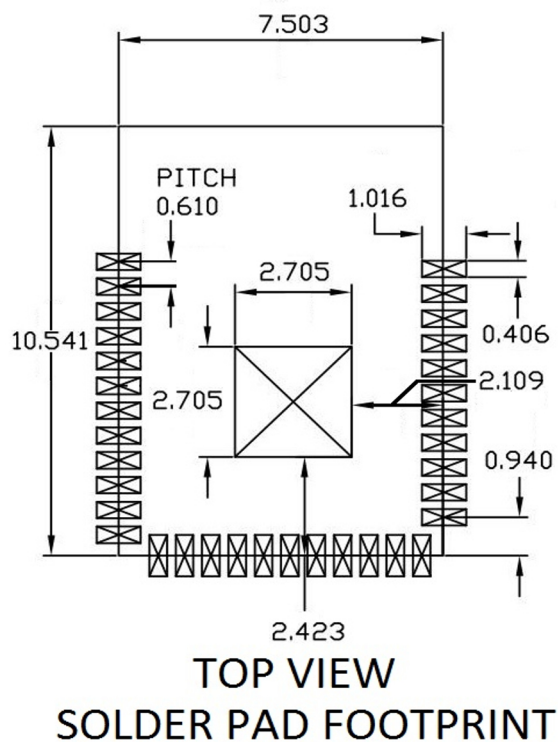
12.2 ATBTLC1000-ZR110CA Module Package Outline Drawing

Figure 12-2. ATBTLC1000-ZR110CA Module Package Outline Drawing



ATBTLC1000-ZR110CA
 Dimension units: mm
 Untoleranced dimensions.
 Drawing not to scale.

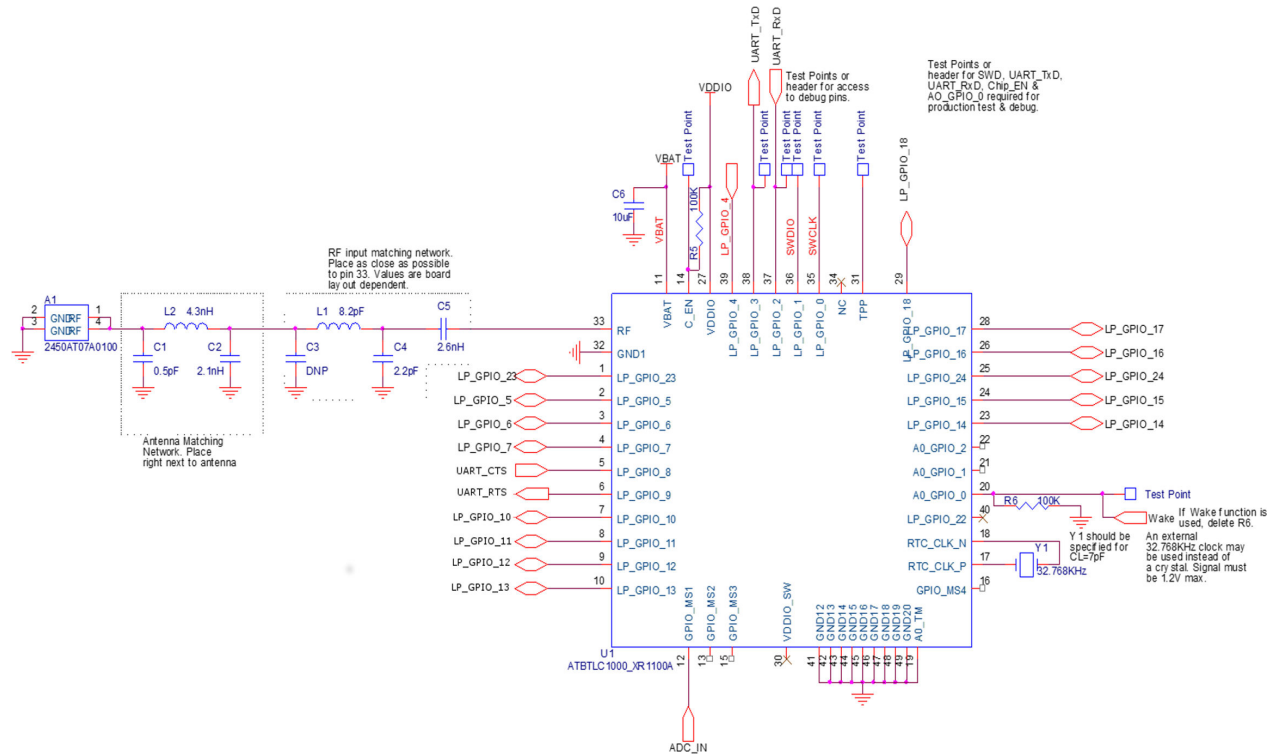
Figure 12-3. Customer PCB Top View Footprint



13. ATBTLC1000 Schematics

13.1 ATBTLC1000-XR1100A Reference Schematic

Figure 13-1. ATBTLC1000-XR1100A Reference Schematic



13.2 ATBTLC1000-XR1100A Reference Schematic Bill of Materials (BOM)

Table 13-1. ATBTLC1000-XR1100A Reference Schematic Bill of Materials (BOM)

Item	Qty	Reference	Value	Description	Manufacturer	Part Number	Footprint
1	1	A1	2450AT07 A0100	1x0.5 mm Ceramic Chip Antenna	Johanson Dielectrics	2450AT07 A0100	
2	1	C1	0.5 pF	CAP, CER, 0.5 pF, +/-0.1 pF, NPO, 0201, 25V, -55-125 C	Johanson Dielectrics	250R05L0 R5BV4T	0201

.....continued

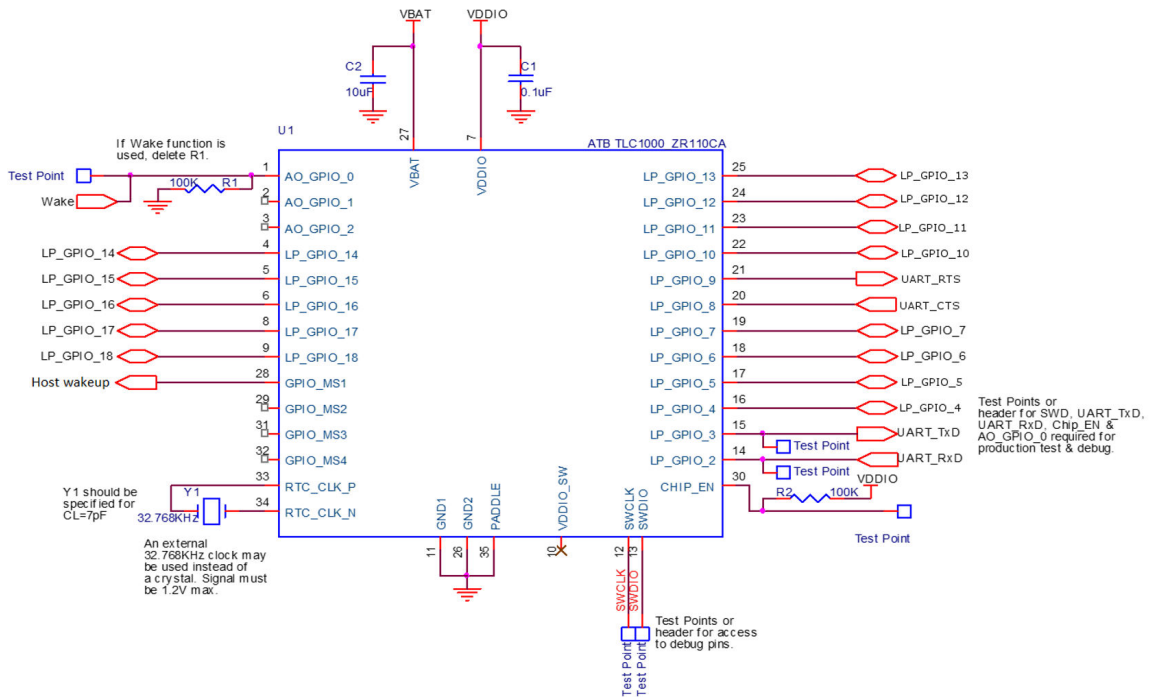
Item	Qty	Reference	Value	Description	Manufacturer	Part Number	Footprint
3	1	C2	2.1 nH	Inductor, 2.1 nH, +/-0.1 nH, Q=14@500 MHz, SRF=11 GHz, 0201, -55-125 C	Murata	LQP03TN2 N1B02D	0201
4	1	C3	DNP	CAP, CER, 2.2 pF, +/-0.1 pF, NPO, 0201, 25V, -55-125C	Johanson Dielectrics	250R05L2 R2BV4T	0201
5	1	C4	2.2 pF	CAP, CER, 2.2 pF, +/-0.1 pF, NPO, 0201, 25V, -55-125 C	Johanson Dielectrics	250R05L2 R2BV4T	0201
6	1	C5	2.6 nH	Inductor, 2.6 nH, +/-0.1 nH, Q=13@500 MHz, SRF=6 GHz, 0201,-55-1 25 C	Murata	LQP03TG2 N6B02D	0201
7	1	C6	10 uF	CAP, CER, 10 uF,20%, X5R, 0603, 6.3V	AVX Corporatio n	06036D106 MAT2A	0603
8	1	L1	8.2 pF	CAP, CER, 8.2 pF, +/-0.1 pF, NPO, 0201, 25V, -55-125 C	Johanson Dielectrics	250R05L8 R2BV4T	0201

.....continued

Item	Qty	Reference	Value	Description	Manufacturer	Part Number	Footprint
9	1	L2	4.3 nH	Inductor, 4.3 nH, +/-3%, Q=13@500 MHz, SRF=6 GHz, 0201, -55-125 C	Murata	LQP03TG4 N3H02D	0201
10	2	R5,R6	100K	RESISTOR , Thick Film, 100 kOhm, 0201	Panasonic ®	ERJ-1GEF 1003C	0201
11	7	TP1,TP2,TP4,TP5,TP6,TP7,TP8	Non- Component	Test Point, Surface Mount, 0.040"sq w/ 0.25"hole		40X40_SM _TEST_PO INT	0.04"SQx0. 025"H
12	1	U1	ATBTLC1000- XR1100A	ATBTLC1000- XR1100A BLE SIP	Microchip Technology Inc	ATBTLC1000- XR1100A	ATBTLC1000- XR1100A
13	1	Y1	32.768 KHz	Crystal, 32.768 KHz, +/-20 ppm, -40- +85C, CL=7 pF, 2 lead, SMD	ECS, Inc. International	ECS-. 327-7-34B- TR	

13.3 ATBTLC1000-ZR110CA Reference Schematic

Figure 13-2. ATBTLC1000-ZR110CA Reference Schematic



13.4 ATBTLC1000-ZR110CA Reference Bill of Materials(BOM)

Table 13-2. ATBTLC1000-ZR110CA Reference Schematic Bill of Materials (BOM)

Item	Qty	Reference	Value	Description	Manufacturer	Part Number	Footprint
1	1	C1	0.1 uF	CAP, CER, 0.1 uF 6.3V +/-10% X5R 0201	AVX Corporation	02016D104KAT2A	0201
7	1	C2	10 uF	CAP, CER, 10 uF, 20%, X5R, 0603, 6.3V	AVX Corporation	06036D106MAT2A	0603
10	2	R1, R2	100 K	RESISTOR, Thick Film, 100 kOhm, 0201	Panasonic®	ERJ-1GEF1003C	0201
12	1	U1	ATBTLC1000_ZR110CA	ATBTLC1000_ZR110CA BLE Module	Microchip Technology Inc	ATBTLC1000_ZR110CA	ATBTLC1000_ZR110CA

.....continued

Item	Qty	Reference	Value	Description	Manufacturer	Part Number	Footprint
13	1	Y1	32.768 KHz	Crystal, 32.768 KHz, +/-20 ppm, -40-+85 C, CL=7 pF, 2 lead, SMD	ECS, Inc. International	ECS- 327-7-34 B-TR	

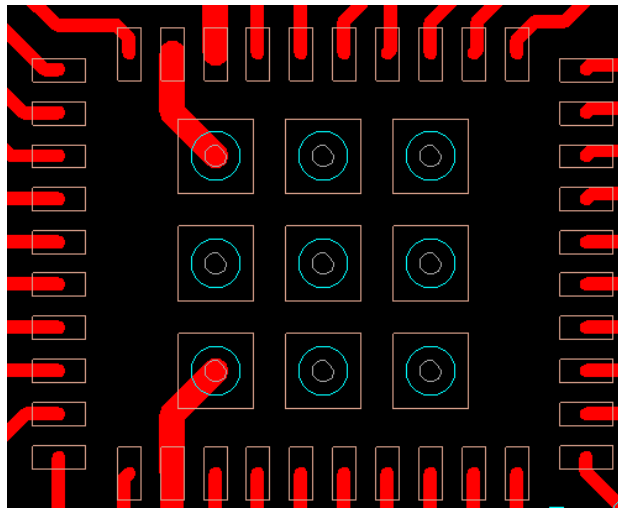
14. ATBTLC1000-XR1100A Design Considerations

The ATBTLC1000-XR1100A is offered in a shielded Land Grid Array (LGA) package with organic laminate substrates. The LGA package makes the second level interconnect (from package to the customer PCB) with an array of solderable surfaces. This may consist of a layout similar to a BGA with no solder spheres. However, it may also have an arbitrary arrangement of solderable surfaces that typically include large planes for grounding or thermal dissipation, smaller lands for signals or shielding grounds, and in some cases, mechanical reinforcement features for mechanical durability.

14.1 Layout Recommendation

Referring to the SiP footprint dimensions in [Figure 12-1](#), it is recommended to use a solder mask defined with PCB pads 0.22 mm wide that have a 0.4 mm pitch. A sample PCB pad layout in following figure shows the required vias for the center ground paddle.

Figure 14-1. PCB Footprint For ATBTLC1000-XR1100A



The land design on the customer PCB should follow the following rules:

1. The solderable area on the customer PCB should match the nominal solderable area on the LGA package 1:1.
2. The solderable area should be finished with organic surface protectant (OSP), NiAu, or a solder cladding.
3. The decision on whether to have a solder mask defined (SMD) land or a non-solder mask defined (NSMD) land depends on the application space.
 - SMD: If field reliability is at risk due to impact failures, such as dropping a hand-held portable application, then the SMD land is recommended to optimize mechanical durability.
 - NSMD: If field reliability is at risk due to a solder fatigue failure (temperature cycle related open circuits), then the NSMD land is recommended to maximize solder joint life.

14.1.1 Power and Ground

Proper grounding is essential for correct operation of the SiP and peak performance. [Figure 12-1](#) shows the bottom view of the ATBTLC1000-XR1100A SiP with exposed ground pads. The SiP exposed ground pads must be soldered to customer PCB ground plane. A solid inner layer ground plane should be provided. The center ground paddle of the SiP must have a grid of ground vias solidly connecting the pad to the inner layer ground plane (one via per exposed center ground pads J41 to J49).

Dedicate one layer as a ground plane, preferably the second layer from the top. Make sure that this ground plane does not get broken up by routes. Power can route on all layers, except the ground layer. Power supply routes should be heavy copper fill planes to ensure the lowest possible inductance. The power pins of the ATBTLC1000-XR1100A should have a via directly to the power plane as close to the pin as possible. Decoupling capacitors should have a via right next to the capacitor pin and this via should go directly down to the power plane – that is to say, the capacitor should not route to the power plane through a long trace. The ground side of the decoupling capacitor should have a via right next to the pad which goes directly down to the ground plane. Each decoupling capacitor should have its own via directly to the ground plane and directly to the power plane right next to the pad. The decoupling capacitors should be placed as close to the pin that it is filtering as possible.

14.1.2 Antenna

When designing the ATBTLC1000-XR1100A, it is important to pay attention to the following recommendations for antenna placement:

1. Make sure to choose an antenna that covers the proper frequency band; 2.400 GHz to 2.500 GHz.
2. Assure that the antenna is designed matched to 50 Ohm input impedance.
3. Talk to the antenna vendor and make sure it is understood that the full frequency range must be covered by the antenna.
4. Be sure to follow the antenna vendors best practice layout recommendations, while placing the antenna in the customer PCB design.
5. The customer PCB pad that the antenna is connected to must be properly designed for 50 Ohm impedance.
6. Make sure that the trace from the RF pin on the ATBTLC1000-XR1100A to the antenna matching circuitry has a 50 Ohm impedance.
7. Do not enclose the antenna within a metal shield.
8. Keep any components that may radiate noise or signals within the 2.4 GHz to 2.5 GHz frequency band far away from the antenna and RF traces or better yet, shield the noisy components. Any noise radiated from the customer PCB in this frequency band will degrade the sensitivity of the ATBTLC1000-XR1100A device.

15. ATBTLC1000-ZR110CA Design Considerations

15.1 Placement and Routing Guidelines

It is critical to follow the recommendations listed below to achieve the best RF performance for the ATBTLC1000-ZR110CA module:

1. The module must be placed on the host board and the chip antenna area must not overlap with the host board. The portion of the module containing the antenna must not stick out over the edge of the host board. [Figure 15-2](#) shows the best, poor and worst-case module placements in host board.
2. Follow the module placement and mechanical cutout recommendation as shown in [Figure 15-1](#).
 - Avoid routing any traces in the highlighted region on the top layer of the host board which will be directly below the module area.
 - Place GND polygon pour below the module with the recommended boundary in the top layer of the host board as shown in [Figure 15-1](#). Do not have any breaks in this GND plane. We recommend having a minimum area of 40x20mm for GND polygon pour in the top layer of the host board.
 - Place sufficient GND vias in the highlighted area below the module for better RF performance.
 - It is recommended to have a 3x3 grid of GND vias solidly connecting the exposed GND paddle of the module to the ground plane on the inner/other layers of the host board. The GND vias should have a minimum via hole size of 0.2mm.
3. Do not enclose the antenna within a metal shield. Keep large metal objects as far away as possible from the antenna, to avoid electromagnetic field blocking.
4. Keep any components which may radiate noise or signals within the 2.4 GHz to 2.5 GHz frequency band away from the antenna and if possible, shield those components. Any noise radiated from the host board in this frequency band will degrade the sensitivity of the module.

Figure 15-1. PCB Keep Out Area

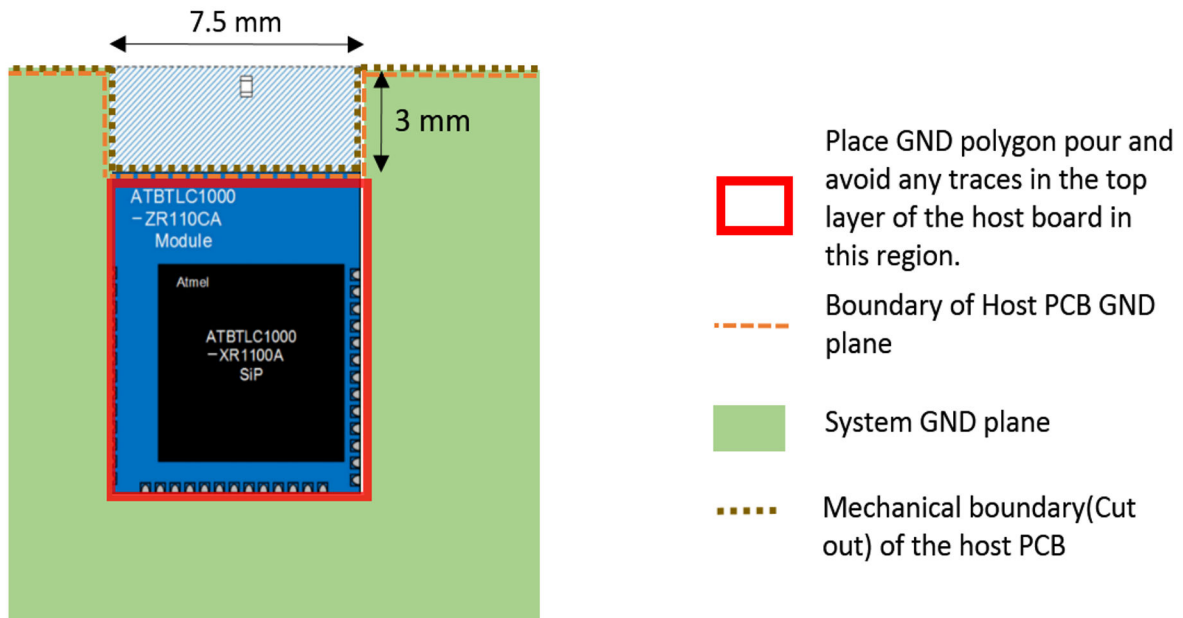
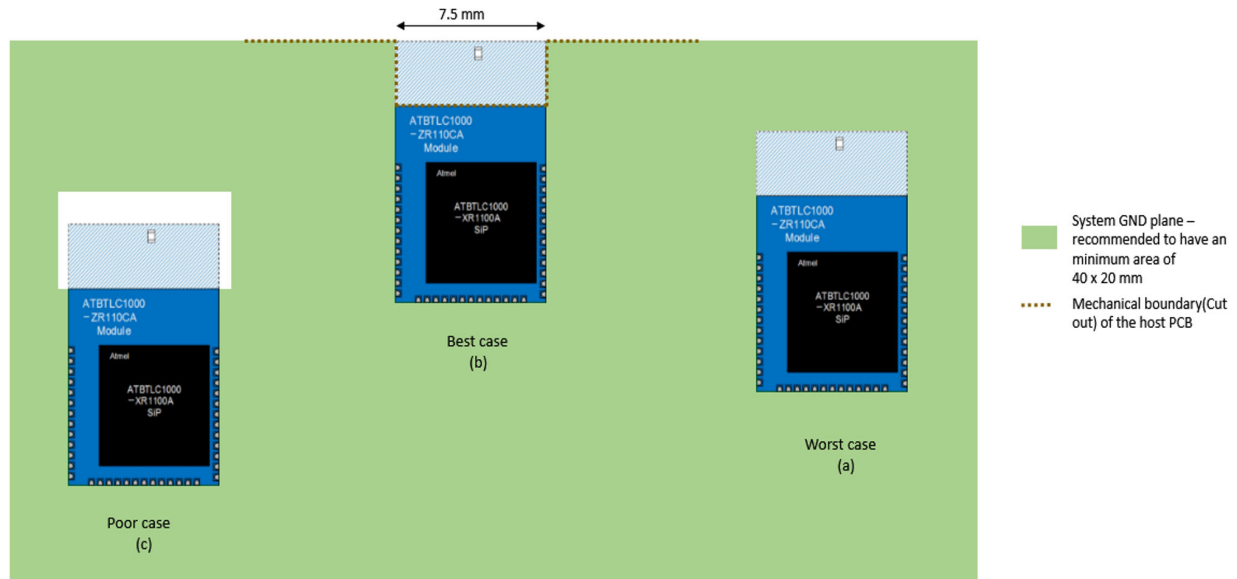


Figure 15-2. ATBTLC1000-ZR110CA Placement Examples



15.2 Interferers

One of the biggest problems with RF devices is poor performance due to interferers on the board radiating noise into the antenna or coupling into the RF traces going to input LNA. Care must be taken to make sure that no noisy circuitry is placed anywhere near the antenna or the RF traces. All noise generating circuits should also be shielded, so that they do not radiate noise that is picked up by the antenna. This applies to all layers. Even if there is a ground plane on a layer between the RF route and another signal, the ground return current will flow on the ground plane and couple into the RF traces.

16. Reflow Profile Information

This section provides guidelines for the reflow process in soldering the ATBTLC1000-XR1100A or the ATBTLC1000-ZR110CA to the customer's design. For more information on reflow process guidelines, refer to the Solder Reflow Recommendation application note ([DS00233D](#)).

16.1 Storage Condition

16.1.1 Before Opening Moisture Barrier Bag

A moisture barrier bag must be stored in a temperature of less than 30°C with humidity under 85% RH.

The calculated shelf life for the dry-packed product shall be 12 months from the date the bag is sealed.

16.1.2 After Opening Moisture Barrier Bag

Humidity indicator cards must be blue, < 30%.

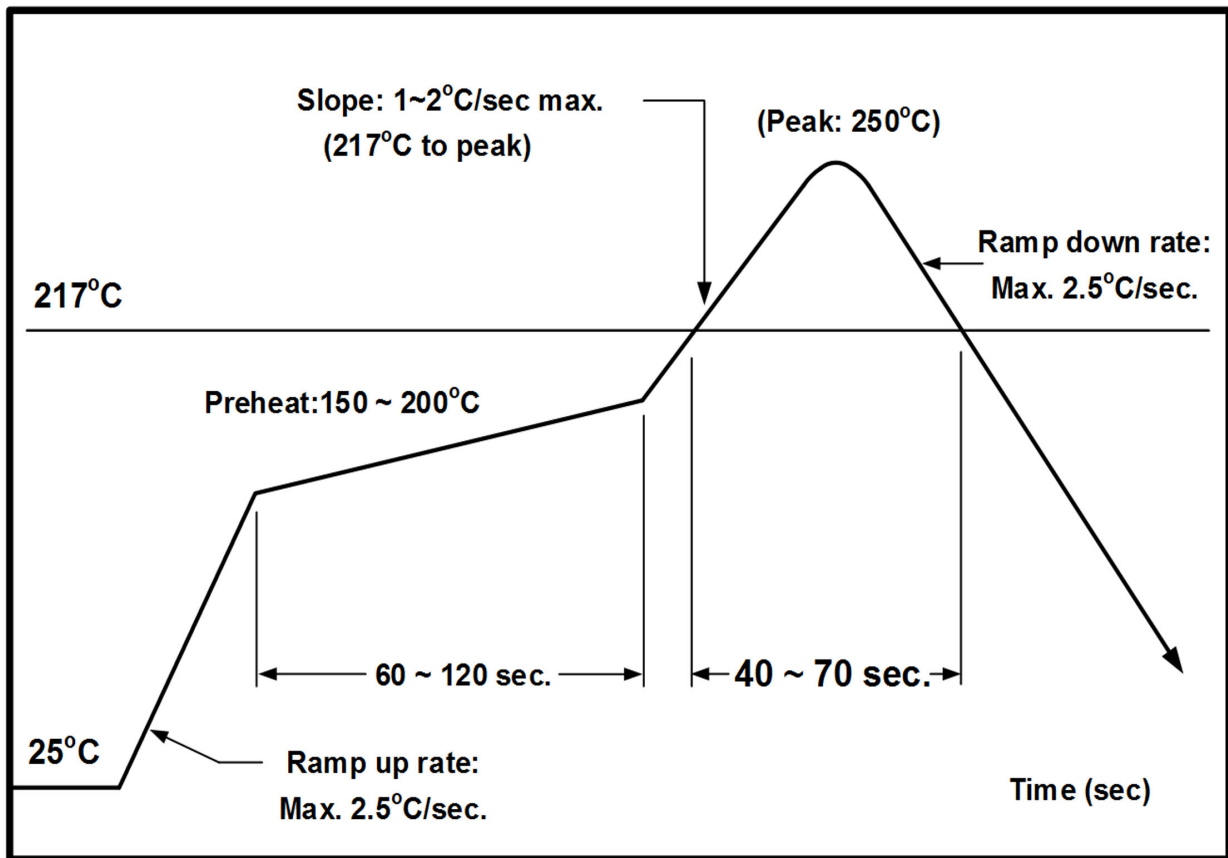
16.2 Soldering and Reflow Conditions

16.2.1 Reflow Oven

The following items should be observed in the reflow process:

- Allowable reflow soldering iterations:
 - Three times based on the following reflow soldering profile (see [Figure 16-1](#))
- Temperature profile:
 - Reflow soldering shall be done according to the following temperature profile (see [Figure 16-1](#))
 - Peak temperature: 250°C

Figure 16-1. Solder Reflow Profile



16.2.2 Cleaning

The exposed ground paddle helps to self-align the module, avoiding pad misalignment. The use of no clean solder pastes is recommended. Full drying of no-clean paste fluxes as a result of the reflow process must be ensured. This may require longer reflow profiles and/or peak temperatures toward the high end of the process window as recommended by the solder paste vendor. It is believed that uncured flux residues could lead to corrosion and/or shorting in accelerated testing and possibly the field.

Note: Solutions like IPA and similar solvents can be used to clean the ATBTLC1000-ZR110CA module. However, cleaning solutions containing acid must never be used on the module.

16.2.3 Rework

Rework is to remove the mounted SiP package and replace with a new unit. It is recommended that once an ATBTLC1000-ZR110CA module has been removed it should never be reused. During the rework process, the mounted module and PCB are heated partially, and the module is removed. It is recommended to pay attention to heat-proof the proximity of the mounted parts and junctions and use the best nozzle for rework that is suited to the module size.

16.3 Baking Conditions

This module is rated at MSL level 3. After the sealed bag is opened, no baking is required within 168 hours, as long as the devices are held at $\leq 30^{\circ}\text{C}/60\% \text{ RH}$ or stored at $<10\% \text{ RH}$.

The module requires baking before mounting if:

- The sealed bag has been open for > 168 hours.
- The Humidity Indicator Card reads >10%.
- SiPs need to be baked for 8 hours at 125°C.

16.4 Module Assembly Considerations

The ATBTLC1000-ZR110CA modules are not intended for use with a conformal coating. The customer assumes all risks if a conformal coating is applied to the modules.

17. Regulatory Approval

Regulatory Approvals received:

ATBTLC1000-ZR110CA

- United States/FCC ID: 2ADHKBTZ
- Canada/ISED
 - IC: 20266- BTLC1000ZR
 - HVIN: ATBTLC1000-ZR110CA
 - PMN: ATBTLC1000-ZR110CA
- Europe/CE
- Japan/MIC: 005-101792
- Korea/KCC: R-CRM-mcp-BTLC1000ZR110C
- Taiwan/NCC: CCAN18LP0510T2

17.1 United States

The ATBTLC1000-ZR110CA module has received Federal Communications Commission (FCC) CFR47 Telecommunications, Part 15 Subpart C “Intentional Radiators” modular approval in accordance with Part 15.212 Modular Transmitter approval. Modular approval allows the end user to integrate the ATBTLC1000-ZR110CA module into a finished product without obtaining subsequent and separate FCC approvals for intentional radiation, provided no changes or modifications are made to the module circuitry. Changes or modifications could void the user’s authority to operate the equipment.

The user must comply with all of the instructions provided by the Grantee, which indicate the installation and/or operating conditions necessary for compliance.

The finished product is required to comply with all applicable FCC equipment authorization regulations, requirements and equipment functions that are not associated with the transmitter module portion. For example, compliance must be demonstrated: to regulations for other transmitter components within a host product; to requirements for unintentional radiators (Part 15 Subpart B), such as digital devices, computer peripherals, radio receivers, etc.; and to additional authorization requirements for the non-transmitter functions on the transmitter module (i.e., Suppliers Declaration of Conformity (SDoC) or Certification) as appropriate (e.g., Bluetooth and Wi-Fi® transmitter modules may also contain digital logic functions).

17.1.1 Labeling And User Information Requirements

Due to the limited module size of ATBTLC1000-ZR110CA (7.503 mm x10.541 mm), the FCC identifier is displayed only in the datasheet and packaging box label. FCC identifier cannot be displayed on the module. When the module is installed inside another device, then the outside of the finished product into which the module is installed must display a label referring to the enclosed module. This exterior label should use the following wording:

For the ATBTLC1000-ZR110CA:

Contains Transmitter Module FCC ID: 2ADHKBTZ

or

Contains FCC ID: 2ADHKBTZ

This device complies with Part 15 of the FCC Rules. Operation is subject to the following two conditions: (1) this device may not cause harmful interference, and (2) this device must accept any interference received, including interference that may cause undesired operation

The user's manual for the product should include the following statement:

This equipment has been tested and found to comply with the limits for a Class B digital device, pursuant to part 15 of the FCC Rules. These limits are designed to provide reasonable protection against harmful interference in a residential installation. This equipment generates, uses and can radiate radio frequency energy, and if not installed and used in accordance with the instructions, may cause harmful interference to radio communications. However, there is no guarantee that interference will not occur in a particular installation. If this equipment does cause harmful interference to radio or television reception, which can be determined by turning the equipment off and on, the user is encouraged to try to correct the interference by one or more of the following measures:

- Reorient or relocate the receiving antenna
- Increase the separation between the equipment and receiver
- Connect the equipment into an outlet on a circuit different from that to which the receiver is connected
- Consult the dealer or an experienced radio/TV technician for help

Additional information on labeling and user information requirements for Part 15 devices can be found in KDB Publication 784748, which is available at the FCC Office of Engineering and Technology (OET) Laboratory Division Knowledge Database (KDB) <https://apps.fcc.gov/oetcf/kdb/index.cfm>

17.1.2 RF Exposure

All transmitters regulated by FCC must comply with RF exposure requirements. KDB 447498 General RF Exposure Guidance provides guidance in determining whether proposed or existing transmitting facilities, operations or devices comply with limits for human exposure to Radio Frequency (RF) fields adopted by the Federal Communications Commission (FCC).

From the FCC Grant: Output power listed is conducted. This grant is valid only when the module is sold to OEM integrators and must be installed by the OEM or OEM integrators.

The module is approved for use in mixed mobile-device and portable-device exposure host platforms. The antenna(s) used with this transmitter must not be co-located or operating in conjunction with any other antenna or transmitter.

17.1.3 Helpful Websites

Federal Communications Commission (FCC): <http://www.fcc.gov>

FCC Office of Engineering and Technology (OET) Laboratory Division Knowledge Database (KDB): <https://apps.fcc.gov/oetcf/kdb/index.cfm>

17.2 Canada

The ATBTLC1000-ZR110CA module has been certified for use in Canada under Innovation, Science, and Economic Development (ISED, formerly Industry Canada) Radio Standards Procedure (RSP) RSP-100, Radio Standards Specification (RSS) RSS-Gen and RSS-247. Modular approval permits the installation of a module in a host device without the need to recertify the device.

17.2.1 Labeling and User Information Requirements

Labeling Requirements (from RSP-100 - Issue 10, Section 3): The host device shall be properly labeled to identify the module within the host device.

Due to the limited module size of ATBTLC1000-ZR110CA (7.503 mm x10.541 mm), the Innovation, Science, and Economic Development Canada certification number identifier is displayed only in the datasheet and packaging box label, and it cannot be displayed on the module.

Therefore, the host product must be labeled to display the Innovation, Science and Economic Development Canada certification number of the module, preceded by the word “Contains” or similar wording expressing the same meaning, as follows:

For the ATBTLC1000-ZR110CA:

Contains IC: 20266-BTLC1000ZR

User Manual Notice for License-Exempt Radio Apparatus (from Section 8.4 RSS-Gen, Issue 4, November 2014): User manuals for license-exempt radio apparatus shall contain the following or equivalent notice in a conspicuous location in the user manual or alternatively on the device or both:

This device complies with Industry Canada license exempt RSS standard(s). Operation is subject to the following two conditions:

- 1. This device may not cause interference, and**
- 2. This device must accept any interference, including interference that may cause undesired operation of the device.**

Le présent appareil est conforme aux CNR d'Industrie Canada applicables aux appareils radio exempts de licence. L'exploitation est autorisée aux deux conditions suivantes:

- 1. l'appareil ne doit pas produire de brouillage, et**
- 2. l'utilisateur de l'appareil doit accepter tout brouillage radioélectrique subi, même si le brouillage est susceptible d'en compromettre le fonctionnement.**

Guidelines on Transmitter Antenna for License Exempt Radio Apparatus:

Under Industry Canada regulations, this radio transmitter may only operate using an antenna of a type and maximum (or lesser) gain approved for the transmitter by Industry Canada. To reduce potential radio interference to other users, the antenna type and its gain should be so chosen that the equivalent isotropically radiated power (e.i.r.p.) is not more than that necessary for successful communication.

Conformément à la réglementation d'Industrie Canada, le présent émetteur radio peut fonctionner avec une antenne d'un type et d'un gain maximal (ou inférieur) approuvé pour l'émetteur par Industrie Canada. Dans le but de réduire les risques de brouillage radioélectrique à l'intention des autres utilisateurs, il faut choisir le type d'antenne et son gain de sorte que la puissance isotrope rayonnée équivalente (p.i.r.e.) ne dépasse pas l'intensité nécessaire à l'établissement d'une communication satisfaisante.

17.2.2 RF Exposure

All transmitters regulated by Innovation, Science and Economic Development Canada (ISED) must comply with RF exposure requirements listed in RSS-102 - Radio Frequency (RF) Exposure Compliance of Radiocommunication Apparatus (All Frequency Bands).

This transmitter is restricted for use with a specific antenna tested in this application for certification, and must not be co-located or operating in conjunction with any other antenna or transmitters within a host device, except in accordance with Canada multi-transmitter product procedures.

The device operates at an output power level which is within ISED SAR test exemption limits at any user distance.

17.2.3 Helpful Websites

Innovation, Science and Economic Development Canada (ISED): <http://www.ic.gc.ca/>

17.3 Europe

The ATBTLC1000-ZR110CA module is a Radio Equipment Directive (RED) assessed radio module that is CE marked and has been manufactured and tested with the intention of being integrated into a final product.

The ATBTLC1000-ZR110CA module has been tested to RED 2014/53/EU Essential Requirements for Health and Safety (Article (3.1(a)), Electromagnetic Compatibility (EMC) (Article 3.1(b)), and Radio (Article 3.2), and are summarized in [Table 17-1](#).

The ETSI provides guidance on modular devices in "*Guide to the application of harmonised standards covering articles 3.1b and 3.2 of the Directive 2014/53/EU (RED) to multi-radio and combined radio and non-radio equipment*" document available at http://www.etsi.org/deliver/etsi_eg/203300_203399/203367/01.01.01_60/eg_203367v010101p.pdf

Note: To maintain conformance to the testing listed in [Table 17-1](#), the module shall be installed in accordance with the installation instructions in this data sheet and shall not be modified. When integrating a radio module into a completed product, the integrator becomes the manufacturer of the final product and is therefore responsible for demonstrating compliance of the final product with the essential requirements against the RED.

17.3.1 Labeling and User Information Requirements

The label on the final product that contains the ATBTLC1000-ZR110CA module must follow CE marking requirements.

Table 17-1. European Compliance Testing (ATBTLC1000-ZR110CA)

Certification	Standards	Article	Laboratory	Report Number	Date
Safety	EN 60950-1:2006 / A11:2009 / A1:2010 / A12:2011 / A2:2013	[3.1(a)]	TUV Rheinland Taiwan	10060745 001	2017-08-04
Health	EN 300 328 V2.1.1 / EN 62479:2010			50080662 001	2017-08-04
EMC	EN 301 489-1 V2.1.1	[3.1(b)]		10060287 002	2017-08-04
	EN 301 489-1 V2.2.0				
	EN 301 489-17 V3.1.1				
	EN 301 489-17 V3.2.0				
Radio	EN 300 328 V2.1.1	(3.2)			50080662 001

17.3.2 Conformity Assessment

From ETSI Guidance Note EG 203367, section 6.1, when non-radio products are combined with a radio product:

If the manufacturer of the combined equipment installs the radio product in a host non-radio product in equivalent assessment conditions (i.e. host equivalent to the one used for the assessment of the radio product) and according to the installation instructions for the radio product, then no additional assessment of the combined equipment against article 3.2 of the RED is required.

The European Compliance Testing listed in [Table 17-1](#) is performed using the integral ceramic chip antenna.

17.3.3 Helpful Websites

A document that can be used as a starting point in understanding the use of Short Range Devices (SRD) in Europe is the European Radio Communications Committee (ERC) Recommendation 70-03 E, which can be downloaded from the European Communications Committee (ECC) at: <http://www.ecodocdb.dk/>

Additional helpful web sites are:

- Radio Equipment Directive (2014/53/EU): https://ec.europa.eu/growth/single-market/european-standards/harmonised-standards/red_en
- European Conference of Postal and Telecommunications Administrations (CEPT): <http://www.cept.org>
- European Telecommunications Standards Institute(ETSI): <http://www.etsi.org>

- The Radio Equipment Directive Compliance Association (REDCA): <http://www.redca.eu/>

17.4 Japan

The ATBTLC1000-ZR110CA module has received type certification and is labeled with its own technical conformity mark and certification number as required to conform to the technical standards regulated by the Ministry of Internal Affairs and Communications (MIC) of Japan pursuant to the Radio Act of Japan.

Integration of this module into a final product does not require additional radio certification provided installation instructions are followed and no modifications of the module are allowed. Additional testing may be required:

- If the host product is subject to electrical appliance safety (for example, powered from an AC mains), the host product may require Product Safety Electrical Appliance and Material (PSE) testing. The integrator must contact their conformance laboratory to determine if this testing is required.
- There is a voluntary Electromagnetic Compatibility (EMC) test for the host product administered by VCCI: http://www.vcci.jp/vcci_e/index.html.

17.4.1 Labeling and User Information Requirements

The label on the final product which contains the ATBTLC1000-ZR110CA module must follow Japan marking requirements. The integrator of the module must refer to the labeling requirements for Japan available at the Ministry of Internal Affairs and Communications (MIC) website.

On the ATBTLC1000-ZR110CA module, due to a limited module size, the technical conformity logo and ID is displayed in the data sheet and/or packaging label and cannot be displayed on the module label. The final product in which this module is being used must have a label referring to the type certified module inside:



17.4.2 Helpful Websites

- Ministry of Internal Affairs and Communications (MIC): <http://www.tele.soumu.go.jp/e/index.htm>.
- Association of Radio Industries and Businesses (ARIB): <http://www.arib.or.jp/english/>.

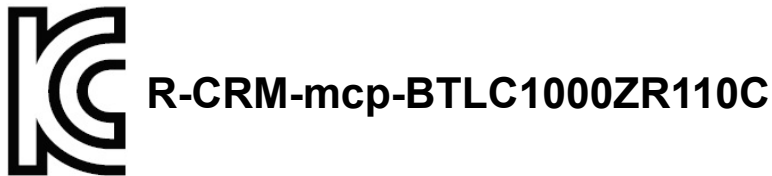
17.5 Korea

The ATBTLC1000-ZR110CA module has received certification of conformity in accordance with the Radio Waves Act. Integration of this module into a final product does not require additional radio certification provided installation instructions are followed and no modifications of the module are allowed.

17.5.1 Labeling and User Information Requirements

The label on the final product which contains the ATBTLC1000-ZR110CA module must follow KC marking requirements. The integrator of the module must refer to the labeling requirements for Korea available on the Korea Communications Commission (KCC) website.

On the ATBTLC1000-ZR110CA module, due to the limited module size, the KC mark and identifier is displayed in the data sheet and/or packaging label, and cannot be displayed on the module label. The final product requires the KC mark and certificate number of the module:



17.5.2 Helpful Websites

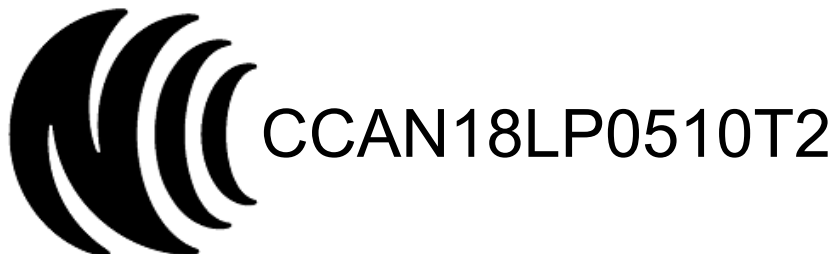
- Korea Communications Commission (KCC): <http://www.kcc.go.kr>
- National Radio Research Agency (RRA): <http://rra.go.kr>

17.6 Taiwan

The ATBTLC1000-ZR110CA module has received compliance approval in accordance with the Telecommunications Act. Customers seeking to use the compliance approval in their product must contact Microchip Technology Inc. sales or distribution partners to obtain a Letter of Authority. Integration of this module into a final product does not require additional radio certification provided installation instructions are followed and no modifications of the module are allowed.

17.6.1 Labeling and User Information Requirements

On the ATBTLC1000-ZR110CA module, due to limited module size, the NCC mark and ID are displayed in the data sheet and/or packaging label and cannot be displayed on the module label.



The user's manual must contain below warning (for RF device) in traditional Chinese:

注意！

依據 低功率電波輻射性電機管理辦法

第十二條 經型式認證合格之低功率射頻電機，非經許可，

公司、商號或使用者均不得擅自變更頻率、加大功率或變更原設計之特性及功能。

第十四條 低功率射頻電機之使用不得影響飛航安全及干擾合法通信；

經發現有干擾現象時，應立即停用，並改善至無干擾時方得繼續使用。

前項合法通信，指依電信規定作業之無線電信。

低功率射頻電機須忍受合法通信或工業、科學及醫療用 電波輻射性

電機設備之干擾。

17.6.2 Helpful Website

- National Communications Commission (NCC): <http://www.ncc.gov.tw>

17.7 Other Regulatory Information

- For information on the other countries jurisdictions covered, refer to the <http://www.microchip.com/design-centers/wireless-connectivity>
- Should other regulatory jurisdiction certification be required by the customer, or the customer need to recertify the module for other reasons, contact Microchip for the required utilities and documentation

18. Reference Documents and Support

18.1 Reference Documents

Microchip offers a set of collateral documentation to ease integration and device ramp. The following table list documents available on Microchip website or integrated into development tools.

Table 18-1. Reference Documents

Title	Content
ATBTLC1000 BluSDK Release Package	This package contains the software development kit and all the necessary documentation including getting started guides for interacting with different hardware devices, device drivers and API call references.
ATBTLC1000 BluSDK BLE API SW Development Guide	This user guide details the functional description of Bluetooth Low Energy (BLE) Application Peripheral Interface (API) programming model. This also provides the example code to configure an API for Generic Access Profile (GAP), Generic Attribute (GATT) Profile, and other services using the ATBTLC1000.
ATBTLC1000 Platform Porting Guide	This document guides the user to port the Application Peripheral Interface (API) into a new platform.
Ultra-Low Power BLE ATBTLC1000-XR1100A SiP Errata	Errata document capturing the known issues with the ATBTLC1000-XR1100A SiP.

For a complete list of development support tools and documentation, visit <http://www.microchip.com>, or contact the nearest Microchip field representative.

19. Document Revision History

Doc Rev.	Date	Comments
DS60001505C	2/2019	- Updated the following sections: 1. Ordering Information 16. Reflow Profile Information, 16.2.1 Reflow Oven, and 16.3 Baking Conditions 16.4 Module Assembly Considerations 17. Regulatory Approval - Added the following sections: 16.2.2 Cleaning and 16.2.3 Rework 17.4 Japan, 17.5 Korea, 17.6 Taiwan, and 17.7 Other Regulatory Information - Updated Bluetooth version to 5.0 as per the QDID 117593.
DS60001505B	4/2018	- Updated 128 KB embedded RAM by removing application memory 96 KB in features section, as this is not valid for ATBTLC1000-XR/ZR - Modified Integrated 2 MHz RC oscillator under clock in features section - Modified 1.88 μA sleep current under ultra-low power in features section - Added BT SIG QDID: 73346 in features section - Updated Ordering details table with Regulatory information - Added Marking information figure of ATBTLC1000-XR1100A - Updated block diagram of ATBTLC1000-ZR110CA - Updated RED report number information and regulatory section as per latest template - Deleted RX peak current information from Table Receiver Performance and TX peak current information from Table Transmitter Performance, as these are already available in Current consumption table - Updated section 15.1 with new placement and routing guidelines, including updated figures. - Updated package information from 40 to 49-pin.

.....continued

Doc Rev.	Date	Comments
DS60001505A	7/2017	- Updated figure Customer PCB Top View Footprint - Updated table ATBTLC1000-XR1100A SiP 40 Package Information with tolerance information and dimensions - Updated pin description for VBAT, RFIO, AO_TM and TPP in Table ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA Pin Description - Modified block diagram to include representation of GPIO_MS pins - Added information related to host wake-up pin in sections Pinout Information, ATBTLC1000-XR/ZR Host Microcontroller Interface and ATBTLC1000 Schematics - Added note to contact technical support for using clock output and RTC XO on chip trimming capacitor configuration - Added regulatory notice for Canada with TBD IC ID - Updated reference schematics to remove the reference to using AO_GPIO_1 and AO_GPIO_2 as wake-up sources as this is not supported - Updated FCCID for the module - Removed references to MCU_Only state as this is not applicable for BTLC1000 - Removed reference to using 2MHz RC Oscillator as Low power clock for applications as this is not supported - Updated the features list for BLE core. SHA-256 has been removed as feature as SHA-256 is not used in BLE security - Added BoM for reference schematic of ATBTLC1000-ZR110CA - Updated power consumption numbers measured based on BluSDK V6.1 - Updated the IC certification details - Migrated to Microchip format. Replaces former Atmel literature number 42749.
42749B	2/2017	Updated tables ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA BLE Receiver Performance and ATBTLC1000-XR1100A and ATBTLC1000-ZR110CA BLE Transmitter Performance
42749A	1/2017	Initial document release

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